

## 混合信号微控制器

### 特性

- 低电源电压范围：**1.8V 至 3.6V**
- 超低功耗
  - 运行模式：**220µA**（在 **1MHz** 频率和 **2.2V** 电压条件下）
  - 待机模式：**0.5µA**
  - 关闭模式（RAM 保持）：**0.1µA**
- **5** 种节能模式
- 可在不到 **1µs** 的时间里超快速地从待机模式唤醒
- **16** 位精简指令集（RISC）架构，**62.5ns** 指令周期时间
- 基本时钟模块配置
  - 具有一个校准频率并高达 **16MHz** 的内部频率
  - 内部极低功率低频（LF）振荡器
  - **32kHz** 晶振<sup>(1)</sup>
  - 外部数字时钟源
- 具有 **2** 个捕捉/比较寄存器的 **16** 位 **Timer\_A**
- 支持 **SPI** 和 **I2C** 的通用串行接口（请见 **Table 1**）
- 欠压检测器
- 带内部基准、采样与保持、和自动扫描功能的 **10** 位 **200** 每秒千次采样（ksps）模数（A/D）转换器（请见 **Table 1**）
- 串行板上编程，  
无需外部编程电压，  
利用安全熔丝实现的可编程代码保护

(1) 晶体振荡器不能在超过 105°C 的环境中运行

(2) 可定制工作温度范围

### 支持国防、航空航天、和医疗应用

- 受控基线
- 一个组装/测试场所
- 一个制造场所
- 支持扩展温度范围（-40°C/125°C）<sup>(2)</sup>
- 延长的产品生命周期
- 延长的产品变更通知
- 产品可追溯性

### 说明

MSP430G2231 是一款包含几个器件的超低功耗微控制器，这几个器件特有针对多种应用的不同外设集。这种架构与 5 种低功耗模式相组合，专为在便携式测量应用中延长电池使用寿命而优化。该器件具有一个强大的 16 位 RISC CPU、16 位寄存器和有助于获得最大编码效率的常数发生器。数字控制振荡器（DCO）可在不到 1µs 的时间里完成从低功耗模式至运行模式的唤醒。

MSP430G2231 有一个 10 位 A/D 转换器和使用同步协议（SPI 或者 I2C）实现的内置通信功能。配置详细信息，请见 **Table 1**。

典型应用包括低成本传感器系统，此类系统负责捕获模拟信号、将之转换为数字值、随后对数据进行处理以进行显示或传送至主机系统。



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**Table 1. Available Options**

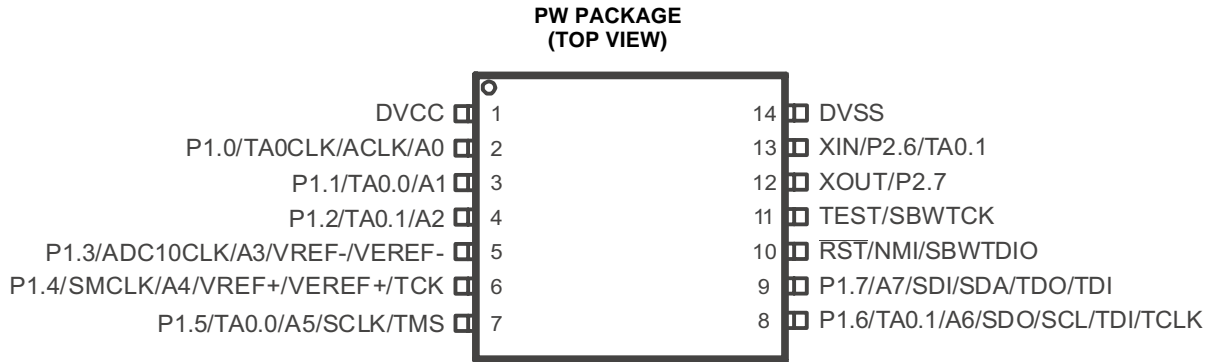
Device	BSL	EEM	Flash (KB)	RAM (B)	Timer_A	USI	ADC10 Channel	Clock	I/O	Package Type
MSP430G2231	-	1	2	128	1x TA2	1	8	LF, DCO, VLO	10	14-TSSOP

**Table 2. ORDERING INFORMATION<sup>(1)</sup>**

T <sub>A</sub>	PACKAGE	ORDERABLE PART NUMBER	TOP-SIDE MARKING	VID NUMBER
-40°C to 125°C	TSSOP - PW	MSP430G2231QPW1EP	G2231EP	V62/12621-01XE

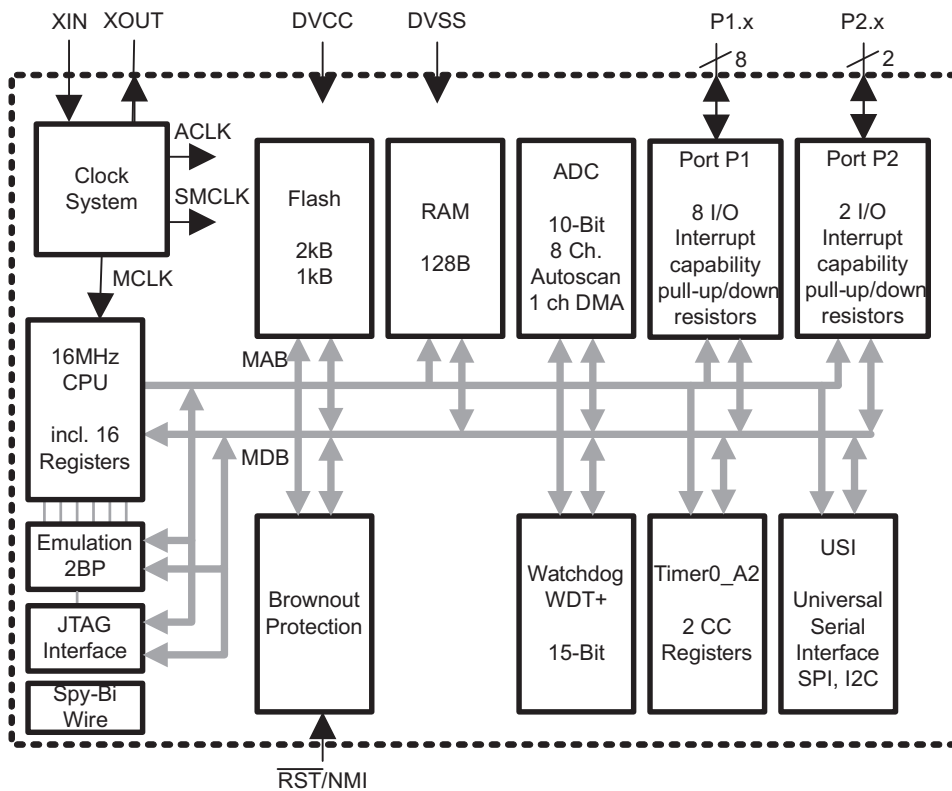
- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI Web site at [www.ti.com](http://www.ti.com).

Device Pinout



NOTE: See port schematics in [Application Information](#) for detailed I/O information.

**Functional Block Diagram**



**Table 3. Terminal Functions**

TERMINAL		I/O	DESCRIPTION
NAME	NO.		
P1.0/ TA0CLK/ ACLK/ A0	2	I/O	General-purpose digital I/O pin Timer0_A, clock signal TACLK input ACLK signal output ADC10 analog input A0 <sup>(1)</sup>
P1.1/ TA0.0/ A1	3	I/O	General-purpose digital I/O pin Timer0_A, capture: CCI0A input, compare: Out0 output ADC10 analog input A1 <sup>(1)</sup>
P1.2/ TA0.1/ A2	4	I/O	General-purpose digital I/O pin Timer0_A, capture: CCI1A input, compare: Out1 output ADC10 analog input A2 <sup>(1)</sup>
P1.3/ ADC10CLK/ A3/ VREF-/VEREF	5	I/O	General-purpose digital I/O pin ADC10, conversion clock output <sup>(1)</sup> ADC10 analog input A3 <sup>(1)</sup> ADC10 negative reference voltage <sup>(1)</sup>
P1.4/ SMCLK/ A4/ VREF+/VEREF+/ TCK	6	I/O	General-purpose digital I/O pin SMCLK signal output ADC10 analog input A4 <sup>(1)</sup> ADC10 positive reference voltage <sup>(1)</sup> JTAG test clock, input terminal for device programming and test
P1.5/ TA0.0/ A5/ SCLK/ TMS	7	I/O	General-purpose digital I/O pin Timer0_A, compare: Out0 output ADC10 analog input A5 <sup>(1)</sup> USI: clock input in I2C mode; clock input/output in SPI mode JTAG test mode select, input terminal for device programming and test
P1.6/ TA0.1/ A6/ SDO/ SCL/ TDI/TCLK	8	I/O	General-purpose digital I/O pin Timer0_A, capture: CCI1A input, compare: Out1 output ADC10 analog input A6 <sup>(1)</sup> USI: Data output in SPI mode USI: I2C clock in I2C mode JTAG test data input or test clock input during programming and test
P1.7/ A7/ SDI/ SDA/ TDO/TDI <sup>(2)</sup>	9	I/O	General-purpose digital I/O pin ADC10 analog input A7 <sup>(1)</sup> USI: Data input in SPI mode USI: I2C data in I2C mode JTAG test data output terminal or test data input during programming and test
XIN/ P2.6/ TA0.1	13	I/O	Input terminal of crystal oscillator General-purpose digital I/O pin Timer0_A, compare: Out1 output
XOUT/ P2.7	12	I/O	Output terminal of crystal oscillator <sup>(3)</sup> General-purpose digital I/O pin
RST/ NMI/ SBWTDIO	10	I	Reset Nonmaskable interrupt input Spy-Bi-Wire test data input/output during programming and test
TEST/ SBWTCK	11	I	Selects test mode for JTAG pins on Port 1. The device protection fuse is connected to TEST. Spy-Bi-Wire test clock input during programming and test
DVCC	1	NA	Supply voltage
DVSS	14	NA	Ground reference
QFN Pad	-	NA	QFN package pad connection to V <sub>SS</sub> recommended.

(1) MSP430G2x31 only

(2) TDO or TDI is selected via JTAG instruction.

(3) If XOUT/P2.7 is used as an input, excess current will flow until P2SEL.7 is cleared. This is due to the oscillator output driver connection to this pad after reset.

## SHORT-FORM DESCRIPTION

### CPU

The MSP430 CPU has a 16-bit RISC architecture that is highly transparent to the application. All operations, other than program-flow instructions, are performed as register operations in conjunction with seven addressing modes for source operand and four addressing modes for destination operand.

The CPU is integrated with 16 registers that provide reduced instruction execution time. The register-to-register operation execution time is one cycle of the CPU clock.

Four of the registers, R0 to R3, are dedicated as program counter, stack pointer, status register, and constant generator, respectively. The remaining registers are general-purpose registers.

Peripherals are connected to the CPU using data, address, and control buses, and can be handled with all instructions.

The instruction set consists of the original 51 instructions with three formats and seven address modes and additional instructions for the expanded address range. Each instruction can operate on word and byte data.

### Instruction Set

The instruction set consists of 51 instructions with three formats and seven address modes. Each instruction can operate on word and byte data. [Table 4](#) shows examples of the three types of instruction formats; [Table 5](#) shows the address modes.

Program Counter	PC/R0
Stack Pointer	SP/R1
Status Register	SR/CG1/R2
Constant Generator	CG2/R3
General-Purpose Register	R4
General-Purpose Register	R5
General-Purpose Register	R6
General-Purpose Register	R7
General-Purpose Register	R8
General-Purpose Register	R9
General-Purpose Register	R10
General-Purpose Register	R11
General-Purpose Register	R12
General-Purpose Register	R13
General-Purpose Register	R14
General-Purpose Register	R15

**Table 4. Instruction Word Formats**

INSTRUCTION FORMAT	SYNTAX	OPERATION
Dual operands, source-destination	ADD R4,R5	R4 + R5 --> R5
Single operands, destination only	CALL R8	PC -->(TOS), R8--> PC
Relative jump, un/conditional	JNE	Jump-on-equal bit = 0

**Table 5. Address Mode Descriptions<sup>(1)</sup>**

ADDRESS MODE	S	D	SYNTAX	EXAMPLE	OPERATION
Register	✓	✓	MOV Rs,Rd	MOV R10,R11	R10 -- --> R11
Indexed	✓	✓	MOV X(Rn),Y(Rm)	MOV 2(R5),6(R6)	M(2+R5) -- --> M(6+R6)
Symbolic (PC relative)	✓	✓	MOV EDE,TONI		M(EDE) -- --> M(TONI)
Absolute	✓	✓	MOV &MEM,&TCDAT		M(MEM) -- --> M(TCDAT)
Indirect	✓		MOV @Rn,Y(Rm)	MOV @R10,Tab(R6)	M(R10) -- --> M(Tab+R6)
Indirect autoincrement	✓		MOV @Rn+,Rm	MOV @R10+,R11	M(R10) -- --> R11 R10 + 2-- --> R10
Immediate	✓		MOV #X,TONI	MOV #45,TONI	#45 -- --> M(TONI)

(1) S = source, D = destination

## Operating Modes

The MSP430 has one active mode and five software selectable low-power modes of operation. An interrupt event can wake up the device from any of the low-power modes, service the request, and restore back to the low-power mode on return from the interrupt program.

The following six operating modes can be configured by software:

- Active mode (AM)
  - All clocks are active
- Low-power mode 0 (LPM0)
  - CPU is disabled
  - ACLK and SMCLK remain active, MCLK is disabled
- Low-power mode 1 (LPM1)
  - CPU is disabled
  - ACLK and SMCLK remain active, MCLK is disabled
  - DCO's dc generator is disabled if DCO not used in active mode
- Low-power mode 2 (LPM2)
  - CPU is disabled
  - MCLK and SMCLK are disabled
  - DCO's dc generator remains enabled
  - ACLK remains active
- Low-power mode 3 (LPM3)
  - CPU is disabled
  - MCLK and SMCLK are disabled
  - DCO's dc generator is disabled
  - ACLK remains active
- Low-power mode 4 (LPM4)
  - CPU is disabled
  - ACLK is disabled
  - MCLK and SMCLK are disabled
  - DCO's dc generator is disabled
  - Crystal oscillator is stopped

## Interrupt Vector Addresses

The interrupt vectors and the power-up starting address are located in the address range 0FFFFh to 0FFC0h. The vector contains the 16-bit address of the appropriate interrupt handler instruction sequence.

If the reset vector (located at address 0FFFEh) contains 0FFFFh (for example, flash is not programmed) the CPU goes into LPM4 immediately after power-up.


**Table 6. Interrupt Sources, Flags, and Vectors**

INTERRUPT SOURCE	INTERRUPT FLAG	SYSTEM INTERRUPT	WORD ADDRESS	PRIORITY
Power-Up External Reset Watchdog Timer+ Flash key violation PC out-of-range <sup>(1)</sup>	PORIFG RSTIFG WDTIFG KEYV <sup>(2)</sup>	Reset	0FFFEh	31, highest
NMI Oscillator fault Flash memory access violation	NMIIFG OFIFG ACCVIFG <sup>(2)(3)</sup>	(non)-maskable (non)-maskable (non)-maskable	0FFFCCh	30
			0FFFAh	29
			0FFF8h	28
			0FFF6h	27
Watchdog Timer+	WDTIFG	maskable	0FFF4h	26
Timer_A2	TACCR0 CCIFG <sup>(4)</sup>	maskable	0FFF2h	25
Timer_A2	TACCR1 CCIFG, TAIFG <sup>(2)(4)</sup>	maskable	0FFF0h	24
			0FFEEh	23
			0FFECCh	22
ADC10	ADC10IFG <sup>(4)</sup>	maskable	0FFEAh	21
USI	USIIFG, USISTTIFG <sup>(2)(4)</sup>	maskable	0FFE8h	20
I/O Port P2 (two flags)	P2IFG.6 to P2IFG.7 <sup>(2)(4)</sup>	maskable	0FFE6h	19
I/O Port P1 (eight flags)	P1IFG.0 to P1IFG.7 <sup>(2)(4)</sup>	maskable	0FFE4h	18
			0FFE2h	17
			0FFE0h	16
See <sup>(5)</sup>			0FFDEh to 0FFC0h	15 to 0, lowest





- (1) A reset is generated if the CPU tries to fetch instructions from within the module register memory address range (0h to 01FFh) or from within unused address ranges.
- (2) Multiple source flags
- (3) (non)-maskable: the individual interrupt-enable bit can disable an interrupt event, but the general interrupt enable cannot.
- (4) Interrupt flags are located in the module.
- (5) The interrupt vectors at addresses 0FFDEh to 0FFC0h are not used in this device and can be used for regular program code if necessary.

## Special Function Registers (SFRs)









Most interrupt and module enable bits are collected into the lowest address space. Special function register bits not allocated to a functional purpose are not physically present in the device. Simple software access is provided with this arrangement.

<b>Legend</b>	<b>rw:</b>	Bit can be read and written.
	<b>rw-0,1:</b>	Bit can be read and written. It is reset or set by PUC.
	<b>rw-(0,1):</b>	Bit can be read and written. It is reset or set by POR.
		SFR bit is not present in device.




**Table 7. Interrupt Enable Register 1 and 2**

Address	7	6	5	4	3	2	1	0
00h			<b>ACCVIE</b>	<b>NMIIE</b>			<b>OFIE</b>	<b>WDTIE</b>
			rw-0	rw-0			rw-0	rw-0









**WDTIE** Watchdog Timer interrupt enable. Inactive if watchdog mode is selected. Active if Watchdog Timer is configured in interval timer mode.  
**OFIE** Oscillator fault interrupt enable  
**NMIIE** (Non)maskable interrupt enable  
**ACCVIE** Flash access violation interrupt enable

Address	7	6	5	4	3	2	1	0
01h								

**Table 8. Interrupt Flag Register 1 and 2**

Address	7	6	5	4	3	2	1	0
02h				<b>NMIIFG</b>	<b>RSTIFG</b>	<b>PORIFG</b>	<b>OFIFG</b>	<b>WDTIFG</b>
				rw-0	rw-(0)	rw-(1)	rw-1	rw-(0)

**WDTIFG** Set on watchdog timer overflow (in watchdog mode) or security key violation. Reset on  $V_{CC}$  power-on or a reset condition at the  $\overline{RST}/NMI$  pin in reset mode.  
**OFIFG** Flag set on oscillator fault.  
**PORIFG** Power-On Reset interrupt flag. Set on  $V_{CC}$  power-up.  
**RSTIFG** External reset interrupt flag. Set on a reset condition at  $\overline{RST}/NMI$  pin in reset mode. Reset on  $V_{CC}$  power-up.  
**NMIIFG** Set via  $\overline{RST}/NMI$  pin

Address	7	6	5	4	3	2	1	0
03h								



## Memory Organization

**Table 9. Memory Organization**

		<b>MSP430G2231</b>
Memory	Size	2kB
Main: interrupt vector	Flash	0xFFFF to 0xFFC0
Main: code memory	Flash	0xFFFF to 0xF800
Information memory	Size	256 Byte
	Flash	010FFh to 01000h
RAM	Size	128B
		027Fh to 0200h
Peripherals	16-bit	01FFh to 0100h
	8-bit	0FFh to 010h
	8-bit SFR	0Fh to 00h

## Flash Memory

The flash memory can be programmed via the Spy-Bi-Wire/JTAG port or in-system by the CPU. The CPU can perform single-byte and single-word writes to the flash memory. Features of the flash memory include:

- Flash memory has n segments of main memory and four segments of information memory (A to D) of 64 bytes each. Each segment in main memory is 512 bytes in size.
- Segments 0 to n may be erased in one step, or each segment may be individually erased.
- Segments A to D can be erased individually or as a group with segments 0 to n. Segments A to D are also called *information memory*.
- Segment A contains calibration data. After reset segment A is protected against programming and erasing. It can be unlocked but care should be taken not to erase this segment if the device-specific calibration data is required.

## Peripherals

Peripherals are connected to the CPU through data, address, and control buses and can be handled using all instructions. For complete module descriptions, see the *MSP430x2xx Family User's Guide (SLAU144)*.

### Oscillator and System Clock

The clock system is supported by the basic clock module that includes support for a 32768-Hz watch crystal oscillator, an internal very-low-power low-frequency oscillator and an internal digitally controlled oscillator (DCO). The basic clock module is designed to meet the requirements of both low system cost and low power consumption. The internal DCO provides a fast turn-on clock source and stabilizes in less than 1 $\mu$ s. The basic clock module provides the following clock signals:

- Auxiliary clock (ACLK), sourced either from a 32768-Hz watch crystal or the internal LF oscillator.
- Main clock (MCLK), the system clock used by the CPU.
- Sub-Main clock (SMCLK), the sub-system clock used by the peripheral modules.

**Table 10. DCO Calibration Data  
(Provided From Factory In Flash Information Memory Segment A)**

DCO FREQUENCY	CALIBRATION REGISTER	SIZE	ADDRESS
1 MHz	CALBC1_1MHZ	byte	010FFh
	CALDCO_1MHZ	byte	010FEh

### Brownout

The brownout circuit is implemented to provide the proper internal reset signal to the device during power on and power off.

### Digital I/O

There is one 8-bit I/O port implemented—port P1—and two bits of I/O port P2:

- All individual I/O bits are independently programmable.
- Any combination of input, output, and interrupt condition is possible.
- Edge-selectable interrupt input capability for all the eight bits of port P1 and the two bits of port P2.
- Read/write access to port-control registers is supported by all instructions.
- Each I/O has an individually programmable pull-up/pull-down resistor.

### WDT+ Watchdog Timer

The primary function of the watchdog timer (WDT+) module is to perform a controlled system restart after a software problem occurs. If the selected time interval expires, a system reset is generated. If the watchdog function is not needed in an application, the module can be disabled or configured as an interval timer and can generate interrupts at selected time intervals.

## Timer\_A2

Timer\_A2 is a 16-bit timer/counter with two capture/compare registers. Timer\_A2 can support multiple capture/compares, PWM outputs, and interval timing. Timer\_A2 also has extensive interrupt capabilities. Interrupts may be generated from the counter on overflow conditions and from each of the capture/compare registers.

**Table 11. Timer\_A2 Signal Connections – Device With ADC10**

INPUT PIN NUMBER	DEVICE INPUT SIGNAL	MODULE INPUT NAME	MODULE BLOCK	MODULE OUTPUT SIGNAL	OUTPUT PIN NUMBER
2 - P1.0	TACLK	TACLK	Timer	NA	
	ACLK	ACLK			
	SMCLK	SMCLK			
2 - P1.0	TACLK	INCLK			
3 - P1.1	TA0	CCI0A	CCR0	TA0	3 - P1.1
	ACLK (internal)	CCI0B			7 - P1.5
	VSS	GND			
	VCC	VCC			
4 - P1.2	TA1	CCI1A	CCR1	TA1	4 - P1.2
8 - P1.6	TA1	CCI1B			8 - P1.6
	VSS	GND			13 - P2.6
	VCC	VCC			

## USI

The universal serial interface (USI) module is used for serial data communication and provides the basic hardware for synchronous communication protocols like SPI and I2C.

## ADC10 (MSP430G2x31 only)

The ADC10 module supports fast, 10-bit analog-to-digital conversions. The module implements a 10-bit SAR core, sample select control, reference generator and data transfer controller, or DTC, for automatic conversion result handling, allowing ADC samples to be converted and stored without any CPU intervention.

## Peripheral File Map

Table 12. Peripherals With Word Access

MODULE	REGISTER DESCRIPTION	REGISTER NAME	OFFSET
<b>ADC10</b>	ADC data transfer start address	ADC10SA	1BCh
	ADC control 0	ADC10CTL0	01B0h
	ADC control 1	ADC10CTL0	01B2h
	ADC memory	ADC10MEM	01B4h
<b>Timer_A</b>	Capture/compare register	TACCR1	0174h
	Capture/compare register	TACCR0	0172h
	Timer_A register	TAR	0170h
	Capture/compare control	TACCTL1	0164h
	Capture/compare control	TACCTL0	0162h
	Timer_A control	TACTL	0160h
	Timer_A interrupt vector	TAIV	012Eh
<b>Flash Memory</b>	Flash control 3	FCTL3	012Ch
	Flash control 2	FCTL2	012Ah
	Flash control 1	FCTL1	0128h
<b>Watchdog Timer+</b>	Watchdog/timer control	WDTCTL	0120h

Table 13. Peripherals With Byte Access

MODULE	REGISTER DESCRIPTION	REGISTER NAME	OFFSET
<b>ADC10</b>	ADC analog enable	ADC10AE0	04Ah
	ADC data transfer control 1	ADC10DTC1	049h
	ADC data transfer control 0	ADC10DTC0	048h
<b>USI</b>	USI control 0	USICTL0	078h
	USI control 1	USICTL1	079h
	USI clock control	USICKCTL	07Ah
	USI bit counter	USICNT	07Bh
	USI shift register	USISR	07Ch
<b>Basic Clock System+</b>	Basic clock system control 3	BCSCTL3	053h
	Basic clock system control 2	BCSCTL2	058h
	Basic clock system control 1	BCSCTL1	057h
	DCO clock frequency control	DCOCTL	056h
<b>Port P2</b>	Port P2 resistor enable	P2REN	02Fh
	Port P2 selection	P2SEL	02Eh
	Port P2 interrupt enable	P2IE	02Dh
	Port P2 interrupt edge select	P2IES	02Ch
	Port P2 interrupt flag	P2IFG	02Bh
	Port P2 direction	P2DIR	02Ah
	Port P2 output	P2OUT	029h
	Port P2 input	P2IN	028h

**Table 13. Peripherals With Byte Access (continued)**

<b>MODULE</b>	<b>REGISTER DESCRIPTION</b>	<b>REGISTER NAME</b>	<b>OFFSET</b>
<b>Port P1</b>	Port P1 resistor enable	P1REN	027h
	Port P1 selection	P1SEL	026h
	Port P1 interrupt enable	P1IE	025h
	Port P1 interrupt edge select	P1IES	024h
	Port P1 interrupt flag	P1IFG	023h
	Port P1 direction	P1DIR	022h
	Port P1 output	P1OUT	021h
	Port P1 input	P1IN	020h
<b>Special Function</b>	SFR interrupt flag 2	IFG2	003h
	SFR interrupt flag 1	IFG1	002h
	SFR interrupt enable 2	IE2	001h
	SFR interrupt enable 1	IE1	000h

### Absolute Maximum Ratings<sup>(1)</sup>

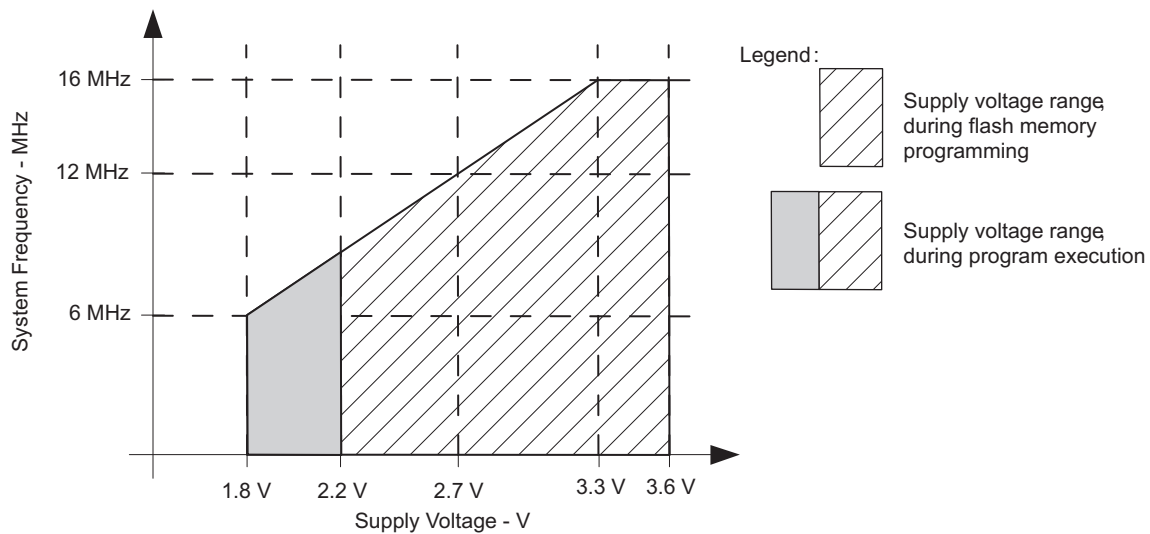
Voltage applied at V <sub>CC</sub> to V <sub>SS</sub>		-0.3 V to 4.1 V
Voltage applied to any pin <sup>(2)</sup>		-0.3 V to V <sub>CC</sub> + 0.3 V
Diode current at any device pin		±2 mA
Storage temperature range, T <sub>stg</sub> <sup>(3)</sup>	Unprogrammed device	-55°C to 150°C
	Programmed device	-55°C to 150°C

- (1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltages referenced to V<sub>SS</sub>. The JTAG fuse-blow voltage, V<sub>FB</sub>, is allowed to exceed the absolute maximum rating. The voltage is applied to the TEST pin when blowing the JTAG fuse.
- (3) Higher temperature may be applied during board soldering according to the current JEDEC J-STD-020 specification with peak reflow temperatures not higher than classified on the device label on the shipping boxes or reels.

### Recommended Operating Conditions

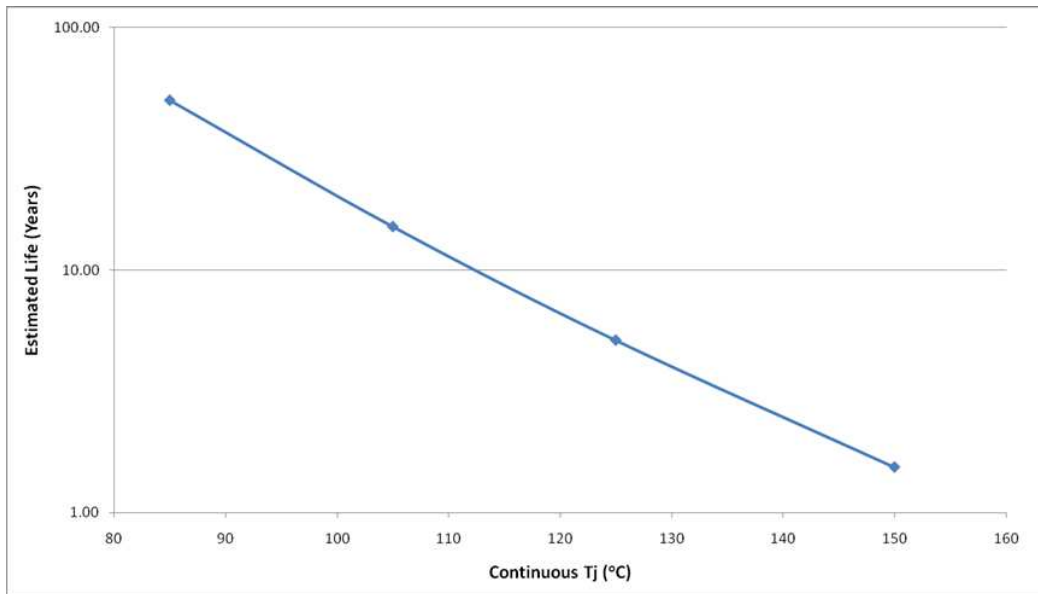
		MIN	NOM	MAX	UNIT
V <sub>CC</sub>	Supply voltage	During program execution	1.8	3.6	V
		During flash programming	2.2	3.6	
V <sub>SS</sub>	Supply voltage	0			V
T <sub>A</sub>	Operating free-air temperature	-40		125	°C
f <sub>SYSTEM</sub>	Processor frequency (maximum MCLK frequency) <sup>(1)(2)</sup>	V <sub>CC</sub> = 1.8 V, Duty cycle = 50% ± 10%	dc	6	MHz
		V <sub>CC</sub> = 2.7 V, Duty cycle = 50% ± 10%	dc	12	
		V <sub>CC</sub> = 3.3 V, Duty cycle = 50% ± 10%	dc	16	

- (1) The MSP430 CPU is clocked directly with MCLK. Both the high and low phase of MCLK must not exceed the pulse width of the specified maximum frequency.
- (2) Modules might have a different maximum input clock specification. See the specification of the respective module in this data sheet.



Note: Minimum processor frequency is defined by system clock. Flash program or erase operations require a minimum V<sub>CC</sub> of 2.2 V.

Figure 1. Safe Operating Area



- A. See data sheet for absolute maximum and minimum recommended operating conditions.
- B. Silicon operating life design goal is 10 years at 110°C junction temperature (does not include package interconnect life).
- C. The predicted operating lifetime vs. junction temperature is based on reliability modeling using electromigration as the dominant failure mechanism affecting device wearout for the specific device process and design characteristics.

Figure 2. Operating Life Derating Chart

## THERMAL INFORMATION

THERMAL METRIC <sup>(1)</sup>		MSP430G2231	UNITS
		PW	
		14 PINS	
$\theta_{JA}$	Junction-to-ambient thermal resistance <sup>(2)</sup>	102.5	°C/W
$\theta_{JCTop}$	Junction-to-case (top) thermal resistance <sup>(3)</sup>	31.4	
$\theta_{JB}$	Junction-to-board thermal resistance <sup>(4)</sup>	45.0	
$\psi_{JT}$	Junction-to-top characterization parameter <sup>(5)</sup>	1.8	
$\psi_{JB}$	Junction-to-board characterization parameter <sup>(6)</sup>	44.4	
$\theta_{JCbott}$	Junction-to-case (bottom) thermal resistance <sup>(7)</sup>	N/A	

- (1) 有关传统和全新热度的更多信息，请参阅 *IC 封装热量量 应用报告* (文献号: [SPRA953](#))。
- (2) 在 JESD51-2a 描述的环境中，按照 JESD51-7 的规定，在一个 JEDEC 标准高 K 电路板上进行仿真，从而获得自然对流条件下的结至环境热阻抗。
- (3) 通过在封装顶部模拟一个冷板测试来获得结至芯片外壳 (顶部) 的热阻。不存在特定的 JEDEC 标准测试，但可在 ANSI SEMI 标准 G30-88 中找到内容接近的说明。
- (4) 按照 JESD51-8 中的说明，通过在配有用于控制 PCB 温度的环形冷板夹具的环境中进行仿真，以获得结至电路板的热阻。
- (5) 结至顶部的特征参数，( $\psi_{JT}$ )，估算真实系统中器件的结温，并使用 JESD51-2a (第 6 章和第 7 章) 中描述的程序从仿真数据中提取出该参数以便获得  $\theta_{JA}$ 。
- (6) 结至电路板的特征参数，( $\psi_{JB}$ )，估算真实系统中器件的结温，并使用 JESD51-2a (第 6 章和第 7 章) 中描述的程序从仿真数据中提取出该参数以便获得  $\theta_{JA}$ 。
- (7) 通过在外露 (电源) 焊盘上进行冷板测试仿真来获得结至芯片外壳 (底部) 热阻。不存在特定的 JEDEC 标准测试，但可在 ANSI SEMI 标准 G30-88 中找到了内容接近的说明。

## Electrical Characteristics

### Active Mode Supply Current Into $V_{CC}$ Excluding External Current

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)<sup>(1)</sup>

- (1) All inputs are tied to 0 V or to  $V_{CC}$ . Outputs do not source or sink any current.

**Active Mode Supply Current Into  $V_{CC}$  Excluding External Current (continued)**

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)<sup>(1)</sup>

PARAMETER	TEST CONDITIONS	$V_{CC}$	MIN	TYP	MAX	UNIT
$I_{AM,1MHz}$ Active mode (AM) current (1 MHz)	$f_{DCO} = f_{MCLK} = f_{SMCLK} = 1\text{ MHz}$ , $f_{ACLK} = 32768\text{ Hz}$ , Program executes in flash, $BCSCTL1 = CALBC1\_1MHz$ , $DCOCTL = CALDCO\_1MHz$ , $CPUOFF = 0$ , $SCG0 = 0$ , $SCG1 = 0$ , $OSCOFF = 0$	2.2 V		220		$\mu A$
		3 V		300	390	

**Typical Characteristics – Active Mode Supply Current (Into  $V_{CC}$ )**

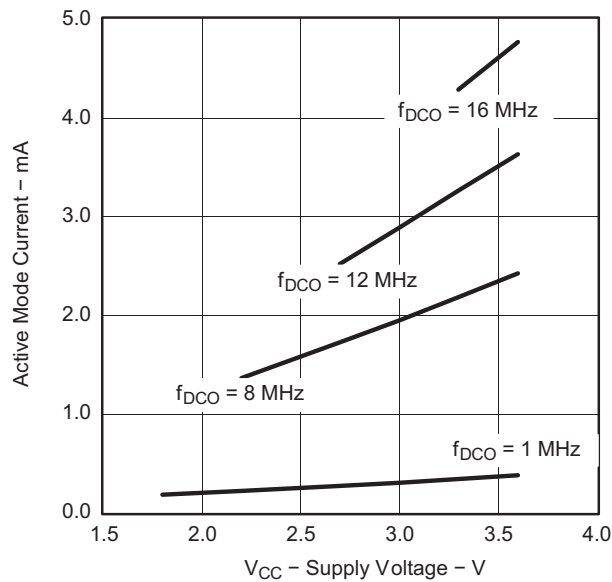


Figure 3. Active Mode Current vs  $V_{CC}$ ,  $T_A = 25^\circ C$

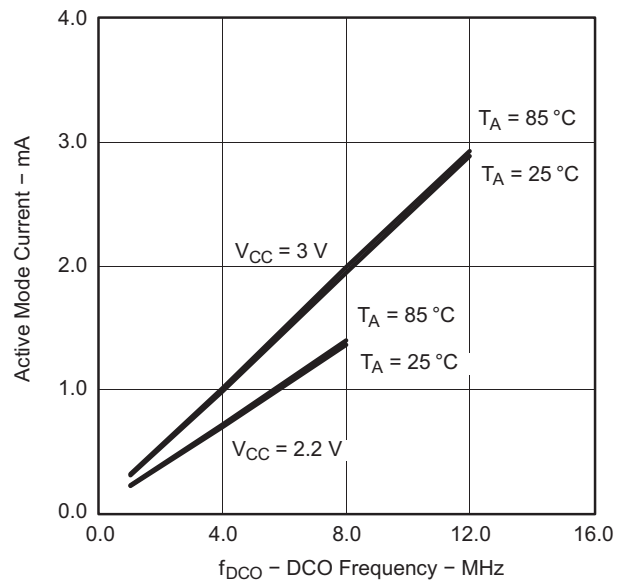


Figure 4. Active Mode Current vs DCO Frequency



### Low-Power Mode Supply Currents (Into $V_{CC}$ ) Excluding External Current

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)<sup>(1)</sup>

PARAMETER	TEST CONDITIONS	$T_A$	$V_{CC}$	MIN	TYP	MAX	UNIT
$I_{LPM0,1MHz}$ Low-power mode 0 (LPM0) current <sup>(2)</sup>	$f_{MCLK} = 0$ MHz, $f_{SMCLK} = f_{DCO} = 1$ MHz, $f_{ACLK} = 32768$ Hz, BCSCTL1 = CALBC1_1MHZ, DCOCTL = CALDCO_1MHZ, CPUOFF = 1, SCG0 = 0, SCG1 = 0, OSCOFF = 0	25°C	2.2 V		65		$\mu$ A
$I_{LPM2}$ Low-power mode 2 (LPM2) current <sup>(3)</sup>	$f_{MCLK} = f_{SMCLK} = 0$ MHz, $f_{DCO} = 1$ MHz, $f_{ACLK} = 32768$ Hz, BCSCTL1 = CALBC1_1MHZ, DCOCTL = CALDCO_1MHZ, CPUOFF = 1, SCG0 = 0, SCG1 = 1, OSCOFF = 0	25°C 125°C	2.2 V		22 46		$\mu$ A
$I_{LPM3,LFXT1}$ Low-power mode 3 (LPM3) current <sup>(3)</sup>	$f_{DCO} = f_{MCLK} = f_{SMCLK} = 0$ MHz, $f_{ACLK} = 32768$ Hz, CPUOFF = 1, SCG0 = 1, SCG1 = 1, OSCOFF = 0	25°C 125°C	2.2 V		0.7 3	1.5 21	$\mu$ A
$I_{LPM3,VLO}$ Low-power mode 3 current, (LPM3) <sup>(3)</sup>	$f_{DCO} = f_{MCLK} = f_{SMCLK} = 0$ MHz, $f_{ACLK}$ from internal LF oscillator (VLO), CPUOFF = 1, SCG0 = 1, SCG1 = 1, OSCOFF = 0	25°C 125°C	2.2 V		0.5 2	0.7 9.3	$\mu$ A
$I_{LPM4}$ Low-power mode 4 (LPM4) current <sup>(4)</sup>	$f_{DCO} = f_{MCLK} = f_{SMCLK} = 0$ MHz, $f_{ACLK} = 0$ Hz, CPUOFF = 1, SCG0 = 1, SCG1 = 1, OSCOFF = 1	25°C 85°C 125°C	2.2 V		0.1 0.8 2	0.5 1.5 7.1	$\mu$ A

- (1) All inputs are tied to 0 V or to  $V_{CC}$ . Outputs do not source or sink any current.
- (2) Current for brownout and WDT clocked by SMCLK included.
- (3) Current for brownout and WDT clocked by ACLK included.
- (4) Current for brownout included.

### Typical Characteristics Low-Power Mode Supply Currents

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

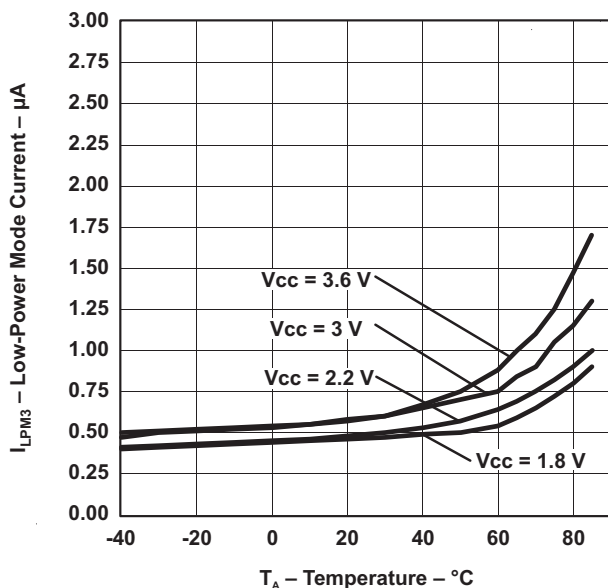


Figure 5. LPM3 Current vs Temperature

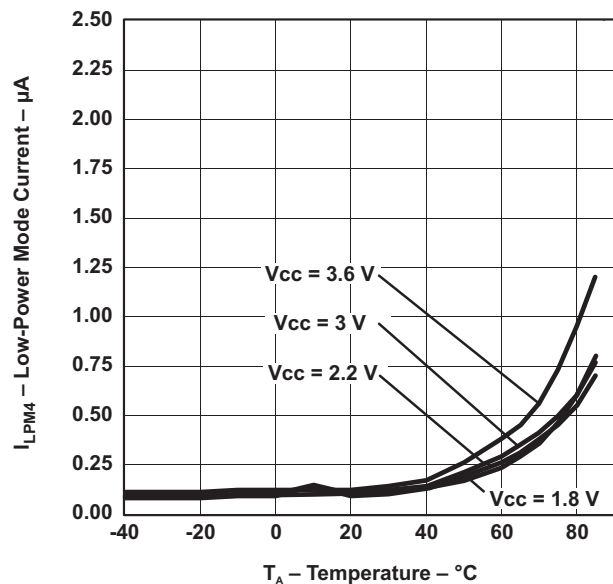


Figure 6. LPM4 Current vs Temperature

## Schmitt-Trigger Inputs – Ports Px

over recommended ranges of supply voltage and up to operating free-air temperature,  $T_A = 105^\circ\text{C}$  (unless otherwise noted)

PARAMETER	TEST CONDITIONS	$V_{CC}$	MIN	TYP	MAX	UNIT
$V_{IT+}$ Positive-going input threshold voltage			$0.45 V_{CC}$		$0.75 V_{CC}$	V
		3 V	1.35		2.25	
$V_{IT-}$ Negative-going input threshold voltage			$0.25 V_{CC}$		$0.55 V_{CC}$	V
		3 V	0.75		1.65	
$V_{hys}$ Input voltage hysteresis ( $V_{IT+} - V_{IT-}$ )		3 V	0.3		1	V
$R_{PULL}$ Pullup/pulldown resistor	For pullup: $V_{IN} = V_{SS}$ For pulldown: $V_{IN} = V_{CC}$	3 V	20	35	50	k $\Omega$
$C_I$ Input capacitance	$V_{IN} = V_{SS}$ or $V_{CC}$			5		pF

## Leakage Current – Ports Px

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	$V_{CC}$	MIN	MAX	UNIT
$I_{lkG}(Px.y)$ High-impedance leakage current <sup>(1)(2)</sup>	$T_A = -40^\circ\text{C}$ to $105^\circ\text{C}$	3 V		$\pm 50$	nA
	$T_A = 125^\circ\text{C}$	3 V		$\pm 120$	

(1) The leakage current is measured with  $V_{SS}$  or  $V_{CC}$  applied to the corresponding pin(s), unless otherwise noted.

(2) The leakage of the digital port pins is measured individually. The port pin is selected for input and the pullup/pulldown resistor is disabled.

## Outputs – Ports Px

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	$V_{CC}$	MIN	TYP	MAX	UNIT
$V_{OH}$ High-level output voltage	$I_{(OHmax)} = -6 \text{ mA}^{(1)}$	3 V		$V_{CC} - 0.3$		V
$V_{OL}$ Low-level output voltage	$I_{(OLmax)} = 6 \text{ mA}^{(1)}$	3 V		$V_{SS} + 0.3$		V

(1) The maximum total current,  $I_{(OHmax)}$  and  $I_{(OLmax)}$ , for all outputs combined should not exceed  $\pm 48 \text{ mA}$  to hold the maximum voltage drop specified.

## Output Frequency – Ports Px

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	$V_{CC}$	MIN	TYP	MAX	UNIT
$f_{Px.y}$ Port output frequency (with load)	$Px.y, C_L = 20 \text{ pF}, R_L = 1 \text{ k}\Omega^{(1)} (2)$	3 V		12		MHz
$f_{Port\_CLK}$ Clock output frequency	$Px.y, C_L = 20 \text{ pF}^{(2)}$	3 V		16		MHz

(1) A resistive divider with  $2 \times 0.5 \text{ k}\Omega$  between  $V_{CC}$  and  $V_{SS}$  is used as load. The output is connected to the center tap of the divider.

(2) The output voltage reaches at least 10% and 90%  $V_{CC}$  at the specified toggle frequency.

### Typical Characteristics – Outputs

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

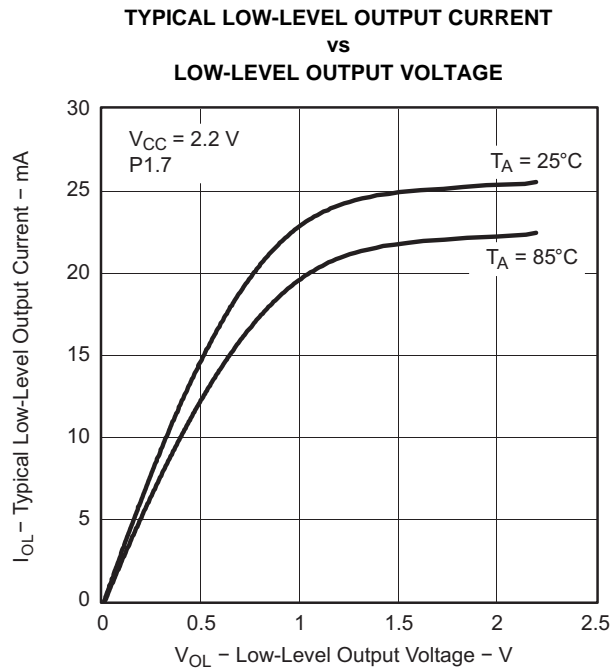


Figure 7.

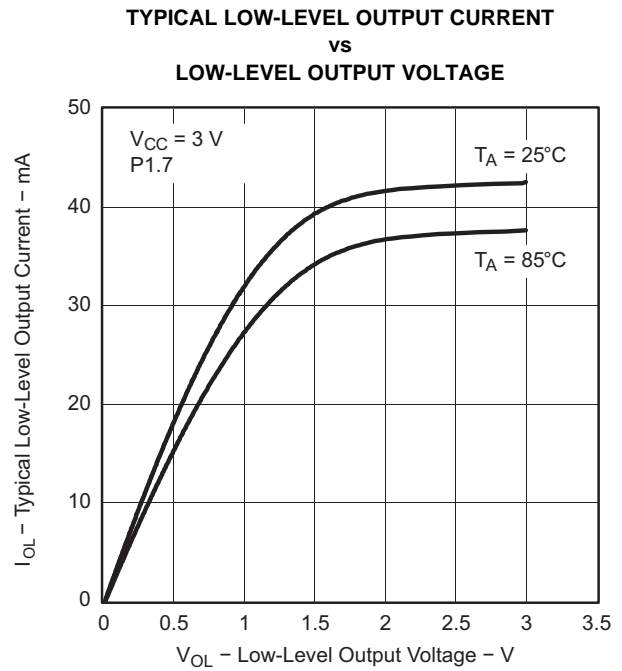


Figure 8.

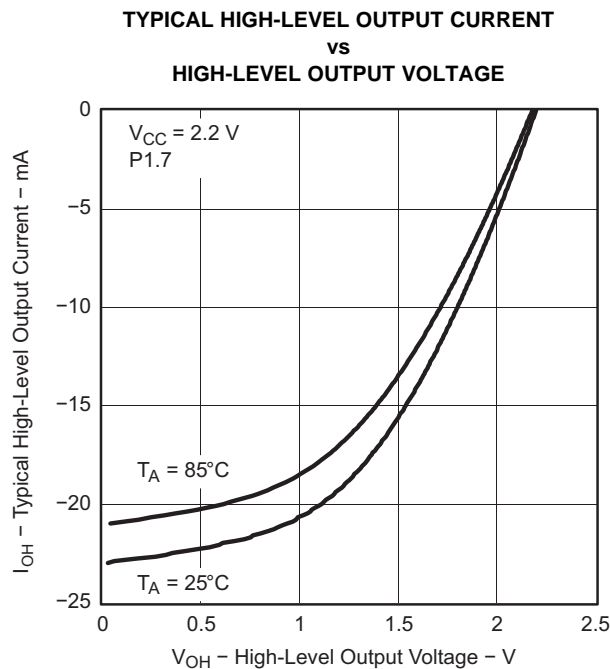


Figure 9.

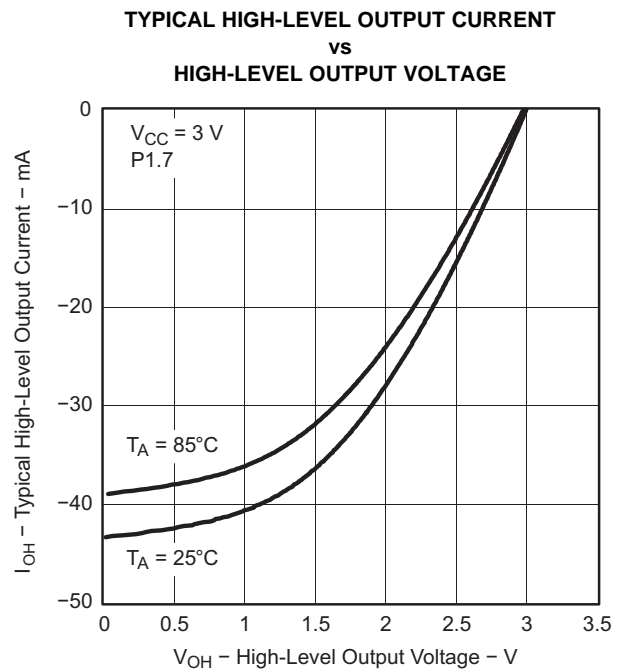


Figure 10.

### POR/Brownout Reset (BOR)<sup>(1)</sup>

over recommended ranges of supply voltage and up to operating free-air temperature,  $T_A = 105^\circ\text{C}$  (unless otherwise noted)

PARAMETER	TEST CONDITIONS	$V_{CC}$	MIN	TYP	MAX	UNIT
$V_{CC(\text{start})}$	See Figure 11	$dV_{CC}/dt \leq 3 \text{ V/s}$		$0.7 \times V_{(B\_IT-)}$		V
$V_{(B\_IT-)}$	See Figure 11 through Figure 13	$dV_{CC}/dt \leq 3 \text{ V/s}$		1.35		V
$V_{\text{hys}(B\_IT-)}$	See Figure 11	$dV_{CC}/dt \leq 3 \text{ V/s}$		130		mV
$t_{d(\text{BOR})}$	See Figure 11				2000	$\mu\text{s}$
$t_{(\text{reset})}$	Pulse length needed at $\overline{\text{RST}}/\text{NMI}$ pin to accepted reset internally	2.2 V/3 V	2			$\mu\text{s}$

(1) The current consumption of the brownout module is already included in the  $I_{CC}$  current consumption data. The voltage level  $V_{(B\_IT-)} + V_{\text{hys}(B\_IT-)is} \leq 1.8 \text{ V}$ .

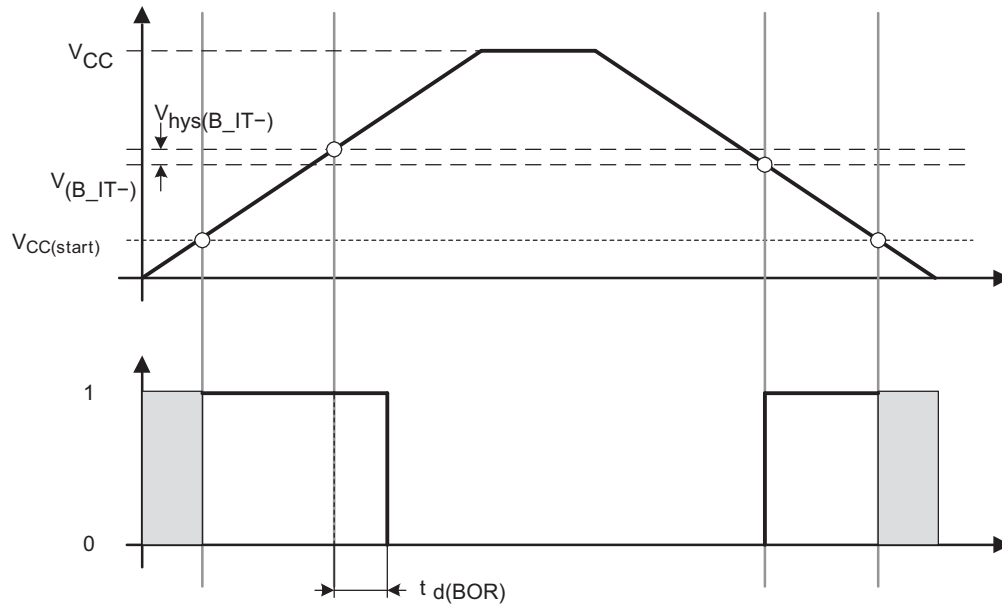


Figure 11. POR/Brownout Reset (BOR) vs Supply Voltage

Typical Characteristics – POR/Brownout Reset (BOR)

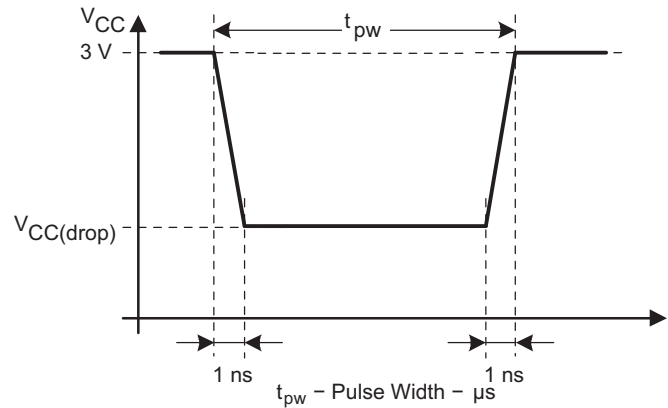
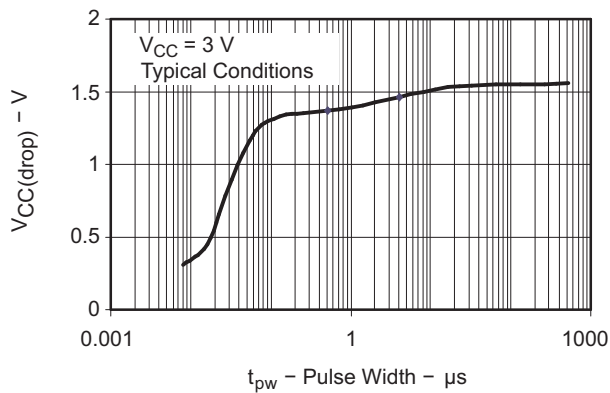


Figure 12.  $V_{CC(drop)}$  Level With a Square Voltage Drop to Generate a POR/Brownout Signal

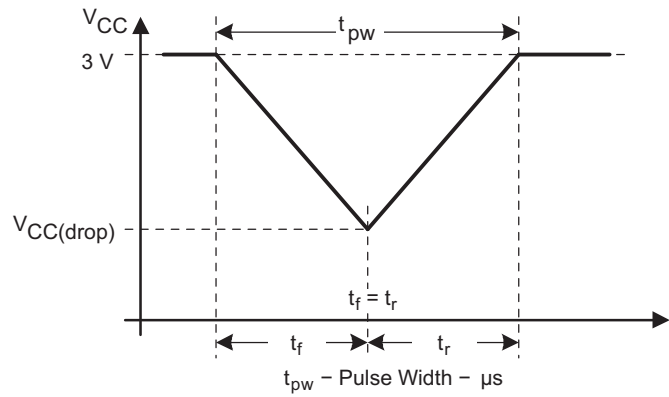
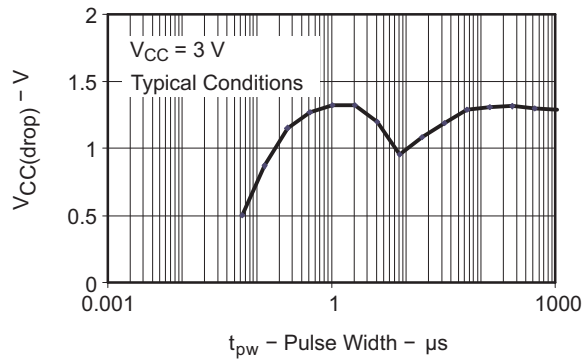


Figure 13.  $V_{CC(drop)}$  Level With a Triangle Voltage Drop to Generate a POR/Brownout Signal

## Main DCO Characteristics

- All ranges selected by RSELx overlap with RSELx + 1: RSELx = 0 overlaps RSELx = 1, ... RSELx = 14 overlaps RSELx = 15.
- DCO control bits DCOx have a step size as defined by parameter S<sub>DCO</sub>.
- Modulation control bits MODx select how often f<sub>DCO(RSEL,DCO+1)</sub> is used within the period of 32 DCOCLK cycles. The frequency f<sub>DCO(RSEL,DCO)</sub> is used for the remaining cycles. The frequency is an average equal to:

$$f_{\text{average}} = \frac{32 \times f_{\text{DCO(RSEL,DCO)}} \times f_{\text{DCO(RSEL,DCO+1)}}}{\text{MOD} \times f_{\text{DCO(RSEL,DCO)}} + (32 - \text{MOD}) \times f_{\text{DCO(RSEL,DCO+1)}}$$

## DCO Frequency

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V <sub>CC</sub>	MIN	TYP	MAX	UNIT
V <sub>CC</sub>	Supply voltage	RSELx < 14		1.8		3.6	V
		RSELx = 14		2.2		3.6	V
		RSELx = 15		3		3.6	V
f <sub>DCO(0,0)</sub>	DCO frequency (0, 0)	RSELx = 0, DCOx = 0, MODx = 0	3 V		0.096		MHz
f <sub>DCO(0,3)</sub>	DCO frequency (0, 3)	RSELx = 0, DCOx = 3, MODx = 0	3 V		0.12		MHz
f <sub>DCO(1,3)</sub>	DCO frequency (1, 3)	RSELx = 1, DCOx = 3, MODx = 0	3 V		0.15		MHz
f <sub>DCO(2,3)</sub>	DCO frequency (2, 3)	RSELx = 2, DCOx = 3, MODx = 0	3 V		0.21		MHz
f <sub>DCO(3,3)</sub>	DCO frequency (3, 3)	RSELx = 3, DCOx = 3, MODx = 0	3 V		0.30		MHz
f <sub>DCO(4,3)</sub>	DCO frequency (4, 3)	RSELx = 4, DCOx = 3, MODx = 0	3 V		0.41		MHz
f <sub>DCO(5,3)</sub>	DCO frequency (5, 3)	RSELx = 5, DCOx = 3, MODx = 0	3 V		0.58		MHz
f <sub>DCO(6,3)</sub>	DCO frequency (6, 3)	RSELx = 6, DCOx = 3, MODx = 0	3 V		0.80		MHz
f <sub>DCO(7,3)</sub>	DCO frequency (7, 3)	RSELx = 7, DCOx = 3, MODx = 0	3 V	0.8		1.5	MHz
f <sub>DCO(8,3)</sub>	DCO frequency (8, 3)	RSELx = 8, DCOx = 3, MODx = 0	3 V		1.6		MHz
f <sub>DCO(9,3)</sub>	DCO frequency (9, 3)	RSELx = 9, DCOx = 3, MODx = 0	3 V		2.3		MHz
f <sub>DCO(10,3)</sub>	DCO frequency (10, 3)	RSELx = 10, DCOx = 3, MODx = 0	3 V		3.4		MHz
f <sub>DCO(11,3)</sub>	DCO frequency (11, 3)	RSELx = 11, DCOx = 3, MODx = 0	3 V		4.25		MHz
f <sub>DCO(12,3)</sub>	DCO frequency (12, 3)	RSELx = 12, DCOx = 3, MODx = 0	3 V	4.3		7.3	MHz
f <sub>DCO(13,3)</sub>	DCO frequency (13, 3)	RSELx = 13, DCOx = 3, MODx = 0	3 V		7.8		MHz
f <sub>DCO(14,3)</sub>	DCO frequency (14, 3)	RSELx = 14, DCOx = 3, MODx = 0	3 V	8.6		13.9	MHz
f <sub>DCO(15,3)</sub>	DCO frequency (15, 3)	RSELx = 15, DCOx = 3, MODx = 0	3 V		15.25		MHz
f <sub>DCO(15,7)</sub>	DCO frequency (15, 7)	RSELx = 15, DCOx = 7, MODx = 0	3 V		21		MHz
S <sub>RSEL</sub>	Frequency step between range RSEL and RSEL+1	S <sub>RSEL</sub> = f <sub>DCO(RSEL+1,DCO)</sub> /f <sub>DCO(RSEL,DCO)</sub>	3 V		1.35		ratio
S <sub>DCO</sub>	Frequency step between tap DCO and DCO+1	S <sub>DCO</sub> = f <sub>DCO(RSEL,DCO+1)</sub> /f <sub>DCO(RSEL,DCO)</sub>	3 V		1.08		ratio
Duty cycle		Measured at SMCLK output	3 V		50		%

### Calibrated DCO Frequencies – Tolerance

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	T <sub>A</sub>	V <sub>CC</sub>	MIN	TYP	MAX	UNIT
1-MHz tolerance over temperature <sup>(1)</sup>	BCSCTL1= CALBC1_1MHz, DCOCTL = CALDCO_1MHz, calibrated at 30°C and 3 V	-40°C to 105°C	3 V	-3	±0.5	+3	%
1-MHz tolerance over V <sub>CC</sub>	BCSCTL1= CALBC1_1MHz, DCOCTL = CALDCO_1MHz, calibrated at 30°C and 3 V	30°C	1.8 V to 3.6 V	-3	±2	+3	%
1-MHz tolerance overall	BCSCTL1= CALBC1_1MHz, DCOCTL = CALDCO_1MHz, calibrated at 30°C and 3 V	-40°C to 105°C	1.8 V to 3.6 V	-6	±3	+6	%

(1) This is the frequency change from the measured frequency at 30°C over temperature.

### Wake-Up From Lower-Power Modes (LPM3/4) – Electrical Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V <sub>CC</sub>	MIN	TYP	MAX	UNIT
t <sub>DCO,LPM3/4</sub> DCO clock wake-up time from LPM3/4 <sup>(1)</sup>	BCSCTL1= CALBC1_1MHz, DCOCTL = CALDCO_1MHz	3 V		1.5		µs
t <sub>CPU,LPM3/4</sub> CPU wake-up time from LPM3/4 <sup>(2)</sup>				1/f <sub>MCLK</sub> + t <sub>Clock,LPM3/4</sub>		

- (1) The DCO clock wake-up time is measured from the edge of an external wake-up signal (for example, port interrupt) to the first clock edge observable externally on a clock pin (MCLK or SMCLK).
- (2) Parameter applicable only if DCOCLK is used for MCLK.

### Typical Characteristics – DCO Clock Wake-Up Time From LPM3/4

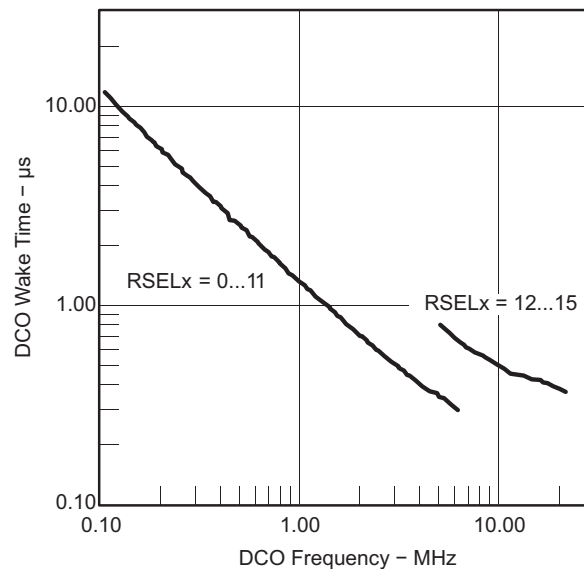


Figure 14. DCO Wake-Up Time From LPM3 vs DCO Frequency

## Crystal Oscillator, XT1, Low-Frequency Mode<sup>(1)</sup>

over recommended ranges of supply voltage and operating free-air temperature,  $T_A = 105^\circ\text{C}$  (unless otherwise noted)

PARAMETER	TEST CONDITIONS	$V_{CC}$	MIN	TYP	MAX	UNIT
$f_{LFXT1,LF}$	LFXT1 oscillator crystal frequency, LF mode 0, 1	1.8 V to 3.6 V		32768		Hz
$f_{LFXT1,LF,logic}$	LFXT1 oscillator logic level square wave input frequency, LF mode	1.8 V to 3.6 V	10000	32768	50000	Hz
$f_{LFXT1,LF,logic}$	LFXT1 oscillator logic level square wave input frequency, LF mode	1.8 V to 3.6 V		32768		Hz
$OA_{LF}$	Oscillation allowance for LF crystals			500		k $\Omega$
				200		
$C_{L,eff}$	Integrated effective load capacitance, LF mode <sup>(2)</sup>			1		pF
				5.5		
				8.5		
				11		
	Duty cycle, LF mode	2.2 V	30	50	70	%
$f_{Fault,LF}$	Oscillator fault frequency, LF mode <sup>(3)</sup>	2.2 V	10		10000	Hz

- (1) To improve EMI on the XT1 oscillator, the following guidelines should be observed.
- Keep the trace between the device and the crystal as short as possible.
  - Design a good ground plane around the oscillator pins.
  - Prevent crosstalk from other clock or data lines into oscillator pins XIN and XOUT.
  - Avoid running PCB traces underneath or adjacent to the XIN and XOUT pins.
  - Use assembly materials and praxis to avoid any parasitic load on the oscillator XIN and XOUT pins.
  - If conformal coating is used, ensure that it does not induce capacitive/resistive leakage between the oscillator pins.
  - Do not route the XOUT line to the JTAG header to support the serial programming adapter as shown in other documentation. This signal is no longer required for the serial programming adapter.
- (2) Includes parasitic bond and package capacitance (approximately 2 pF per pin).  
Since the PCB adds additional capacitance, it is recommended to verify the correct load by measuring the ACLK frequency. For a correct setup, the effective load capacitance should always match the specification of the used crystal.
- (3) Frequencies below the MIN specification set the fault flag. Frequencies above the MAX specification do not set the fault flag. Frequencies in between might set the flag.
- (4) Measured with logic-level input frequency but also applies to operation with crystals.

## Internal Very-Low-Power Low-Frequency Oscillator (VLO)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	$T_A$	$V_{CC}$	MIN	TYP	MAX	UNIT
$f_{VLO}$	-40°C to 85°C	3 V	4	12	20	kHz
	125°C					
$df_{VLO}/dT$	-40°C to 125°C	3 V		0.5		%/°C
$df_{VLO}/dV_{CC}$	25°C	1.8 V to 3.6 V		4		%/V

## Timer\_A

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	$V_{CC}$	MIN	TYP	MAX	UNIT
$f_{TA}$	Internal: SMCLK, ACLK External: TACLK, INCLK Duty cycle = 50% $\pm$ 10%			$f_{SYSTEM}$		MHz
$t_{TA,cap}$	TA0, TA1	3 V	20			ns

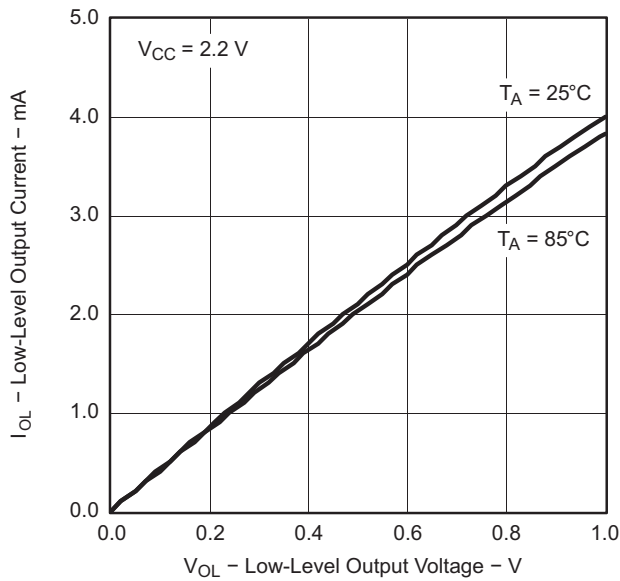


**USI, Universal Serial Interface**

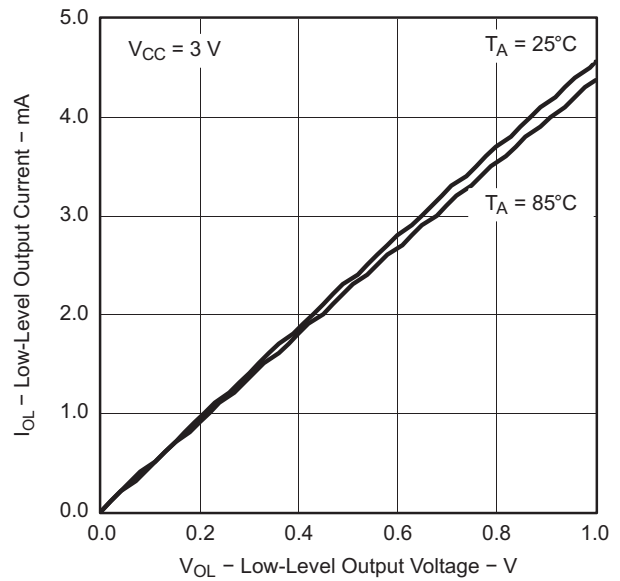
over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V <sub>CC</sub>	MIN	TYP	MAX	UNIT
f <sub>USI</sub>	USI clock frequency	External: SCLK, Duty cycle = 50% ±10%, SPI slave mode		f <sub>SYSTEM</sub>			MHz
V <sub>OL,I2C</sub>	Low-level output voltage on SDA and SCL	USI module in I2C mode, I <sub>(OLmax)</sub> = 1.5 mA	3 V	V <sub>SS</sub>		V <sub>SS</sub> + 0.4	V

**Typical Characteristics – USI Low-Level Output Voltage on SDA and SCL**



**Figure 15. USI Low-Level Output Voltage vs Output Current**



**Figure 16. USI Low-Level Output Voltage vs Output Current**

## 10-Bit ADC, Power Supply and Input Range Conditions

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)<sup>(1)</sup>

PARAMETER	TEST CONDITIONS	T <sub>A</sub>	V <sub>CC</sub>	MIN	TYP	MAX	UNIT	
V <sub>CC</sub>	Analog supply voltage	V <sub>SS</sub> = 0 V		2.2		3.6	V	
V <sub>Ax</sub>	Analog input voltage <sup>(2)</sup>	All Ax terminals, Analog inputs selected in ADC10AE register	3 V	0		V <sub>CC</sub>	V	
I <sub>ADC10</sub>	ADC10 supply current <sup>(3)</sup>	f <sub>ADC10CLK</sub> = 5.0 MHz, ADC10ON = 1, REFON = 0, ADC10SHT0 = 1, ADC10SHT1 = 0, ADC10DIV = 0	3 V		0.6	1.64	mA	
I <sub>REF+</sub>	Reference supply current, reference buffer disabled <sup>(4)</sup>	f <sub>ADC10CLK</sub> = 5.0 MHz, ADC10ON = 0, REF2_5V = 0, REFON = 1, REFOUT = 0	-40°C to 125°C	3 V		0.25	0.84	mA
		f <sub>ADC10CLK</sub> = 5.0 MHz, ADC10ON = 0, REF2_5V = 1, REFON = 1, REFOUT = 0				0.25	0.84	
I <sub>REFB,0</sub>	Reference buffer supply current with ADC10SR = 0 <sup>(4)</sup>	f <sub>ADC10CLK</sub> = 5.0 MHz, ADC10ON = 0, REFON = 1, REF2_5V = 0, REFOUT = 1, ADC10SR = 0	-40°C to 85°C	3 V		1.1	1.4	mA
			-40°C to 125°C				3.8	
I <sub>REFB,1</sub>	Reference buffer supply current with ADC10SR = 1 <sup>(4)</sup>	f <sub>ADC10CLK</sub> = 5.0 MHz, ADC10ON = 0, REFON = 1, REF2_5V = 0, REFOUT = 1, ADC10SR = 1	-40°C to 85°C	3 V		0.5	0.7	mA
			-40°C to 125°C				0.9	
C <sub>I</sub>	Input capacitance	Only one terminal Ax can be selected at one time	-40°C to 125°C	3 V			27	pF
R <sub>I</sub>	Input MUX ON resistance	0 V ≤ V <sub>Ax</sub> ≤ V <sub>CC</sub>	-40°C to 125°C	3 V		1000	2000	Ω

- (1) The leakage current is defined in the leakage current table with Px.y/Ax parameter.
- (2) The analog input voltage range must be within the selected reference voltage range V<sub>R+</sub> to V<sub>R-</sub> for valid conversion results.
- (3) The internal reference supply current is not included in current consumption parameter I<sub>ADC10</sub>.
- (4) The internal reference current is supplied via terminal V<sub>CC</sub>. Consumption is independent of the ADC10ON control bit, unless a conversion is active. The REFON bit enables the built-in reference to settle before starting an A/D conversion.

## 10-Bit ADC, Built-In Voltage Reference

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V <sub>CC</sub>	MIN	TYP	MAX	UNIT
V <sub>CC,REF+</sub>	Positive built-in reference analog supply voltage range		2.2			V
			3			
V <sub>REF+</sub>	Positive built-in reference voltage	3 V	1.4	1.5	1.59	V
			2.34	2.5	2.65	
I <sub>LD,VREF+</sub>	Maximum VREF+ load current <sup>(1)(2)</sup>	3 V			±1	mA
VREF+ load regulation <sup>(1)</sup>	I <sub>VREF+</sub> = 500 µA ± 100 µA, Analog input voltage V <sub>AX</sub> ≠ 0.75 V, REF2_5V = 0	3 V				±2
	I <sub>VREF+</sub> = 500 µA ± 100 µA, Analog input voltage V <sub>AX</sub> ≠ 1.25 V, REF2_5V = 1					±2
V <sub>REF+</sub> load regulation response time <sup>(1)(2)</sup>	I <sub>VREF+</sub> = 100 µA → 900 µA, V <sub>AX</sub> ≠ 0.5 × VREF+, Error of conversion result ≤ 1 LSB, ADC10SR = 0	3 V			400	ns
C <sub>VREF+</sub>	Maximum capacitance at pin VREF+ <sup>(1)(2)</sup>	3 V			100	pF
TC <sub>REF+</sub>	Temperature coefficient	3 V			±190	ppm/°C
t <sub>REFON</sub>	Settling time of internal reference voltage to 99.9% VREF <sup>(1)(2)</sup>	3.6 V			30	µs
t <sub>REFBURST</sub>	Settling time of reference buffer to 99.9% VREF <sup>(1)(2)</sup>	3 V			2	µs

(1) Minimum and maximum parameters are characterized up to T<sub>A</sub> = 105°C, unless otherwise noted.

(2) Characterized at T<sub>A</sub> = -40°C to 105°C only.

## 10-Bit ADC, External Reference<sup>(1)</sup>

over recommended ranges of supply voltage and operating free-air temperature,  $T_A = 105^\circ\text{C}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS	$V_{CC}$	MIN	TYP	MAX	UNIT
VEREF+	Positive external reference input voltage range <sup>(2)</sup>	VEREF+ > VEREF–, SREF1 = 1, SREF0 = 0		1.4		$V_{CC}$	V
		VEREF– ≤ VEREF+ ≤ $V_{CC} - 0.15\text{ V}$ , SREF1 = 1, SREF0 = 1 <sup>(3)</sup>		1.4		3	
VEREF–	Negative external reference input voltage range <sup>(4)</sup>	VEREF+ > VEREF–		0		1.2	V
$\Delta\text{VEREF}$	Differential external reference input voltage range, $\Delta\text{VEREF} = \text{VEREF+} - \text{VEREF-}$	VEREF+ > VEREF– <sup>(5)</sup>		1.4		$V_{CC}$	V
$I_{\text{VEREF+}}$	Static input current into VEREF+	$0\text{ V} \leq \text{VEREF+} \leq V_{CC}$ , SREF1 = 1, SREF0 = 0	3 V		±1		μA
		$0\text{ V} \leq \text{VEREF+} \leq V_{CC} - 0.15\text{ V} \leq 3\text{ V}$ , SREF1 = 1, SREF0 = 1 <sup>(3)</sup>	3 V		0		
$I_{\text{VEREF-}}$	Static input current into VEREF–	$0\text{ V} \leq \text{VEREF-} \leq V_{CC}$	3 V		±1		μA

- (1) The external reference is used during conversion to charge and discharge the capacitance array. The input capacitance,  $C_I$ , is also the dynamic load for an external reference during conversion. The dynamic impedance of the reference supply should follow the recommendations on analog-source impedance to allow the charge to settle for 10-bit accuracy.
- (2) The accuracy limits the minimum positive external reference voltage. Lower reference voltage levels may be applied with reduced accuracy requirements.
- (3) Under this condition the external reference is internally buffered. The reference buffer is active and requires the reference buffer supply current  $I_{\text{REFB}}$ . The current consumption can be limited to the sample and conversion period with REBURST = 1.
- (4) The accuracy limits the maximum negative external reference voltage. Higher reference voltage levels may be applied with reduced accuracy requirements.
- (5) The accuracy limits the minimum external differential reference voltage. Lower differential reference voltage levels may be applied with reduced accuracy requirements.

## 10-Bit ADC, Timing Parameters

over recommended ranges of supply voltage and up to operating free-air temperature,  $T_A = 105^\circ\text{C}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS	$V_{CC}$	MIN	TYP	MAX	UNIT
$f_{\text{ADC10CLK}}$	ADC10 input clock frequency	For specified performance of ADC10 linearity parameters	3 V	ADC10SR = 0	0.45	6.3	MHz
				ADC10SR = 1	0.45	1.5	
$f_{\text{ADC10OSC}}$	ADC10 built-in oscillator frequency	ADC10DIVx = 0, ADC10SSELx = 0, $f_{\text{ADC10CLK}} = f_{\text{ADC10OSC}}$	3 V	3.7		6.3	MHz
$t_{\text{CONVERT}}$	Conversion time	ADC10 built-in oscillator, ADC10SSELx = 0, $f_{\text{ADC10CLK}} = f_{\text{ADC10OSC}}$	3 V	2.06		3.51	μs
		$f_{\text{ADC10CLK}}$ from ACLK, MCLK, or SMCLK, ADC10SSELx ≠ 0				$13 \times \text{ADC10DIV} \times 1/f_{\text{ADC10CLK}}$	
$t_{\text{ADC10ON}}$	Turn-on settling time of the ADC	(1)				100	ns

- (1) The condition is that the error in a conversion started after  $t_{\text{ADC10ON}}$  is less than ±0.5 LSB. The reference and input signal are already settled.

## 10-Bit ADC, Linearity Parameters

over recommended ranges of supply voltage and up to operating free-air temperature,  $T_A = 105^\circ\text{C}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS	$V_{CC}$	MIN	TYP	MAX	UNIT
$E_I$	Integral linearity error		3 V			±1	LSB
$E_D$	Differential linearity error		3 V			±1	LSB
$E_O$	Offset error	Source impedance $R_S < 100\ \Omega$	3 V			±1	LSB
$E_G$	Gain error		3 V		±1.1	±2	LSB
$E_T$	Total unadjusted error		3 V		±2	±5	LSB

## 10-Bit ADC, Temperature Sensor and Built-In $V_{MID}$

over recommended ranges of supply voltage and up to operating free-air temperature,  $T_A = 105^\circ\text{C}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS	$V_{CC}$	MIN	TYP	MAX	UNIT
$I_{SENSOR}$	Temperature sensor supply current <sup>(1)</sup>	REFON = 0, INCHx = 0Ah, $T_A = 25^\circ\text{C}$	3 V		60		$\mu\text{A}$
$TC_{SENSOR}$		ADC10ON = 1, INCHx = 0Ah <sup>(2)</sup>	3 V		3.55		$\text{mV}/^\circ\text{C}$
$t_{Sensor(sample)}$	Sample time required if channel 10 is selected <sup>(3)</sup>	ADC10ON = 1, INCHx = 0Ah, Error of conversion result $\leq 1$ LSB	3 V	30			$\mu\text{s}$
$I_{VMID}$	Current into divider at channel 11	ADC10ON = 1, INCHx = 0Bh	3 V			(4)	$\mu\text{A}$
$V_{MID}$	$V_{CC}$ divider at channel 11	ADC10ON = 1, INCHx = 0Bh, $V_{MID} \neq 0.5 \times V_{CC}$	3 V		1.5		V
$t_{VMID(sample)}$	Sample time required if channel 11 is selected <sup>(5)</sup>	ADC10ON = 1, INCHx = 0Bh, Error of conversion result $\leq 1$ LSB	3 V	1220			ns

- (1) The sensor current  $I_{SENSOR}$  is consumed if (ADC10ON = 1 and REFON = 1) or (ADC10ON = 1 and INCH = 0Ah and sample signal is high). When REFON = 1,  $I_{SENSOR}$  is included in  $I_{REF+}$ . When REFON = 0,  $I_{SENSOR}$  applies during conversion of the temperature sensor input (INCH = 0Ah).
- (2) The following formula can be used to calculate the temperature sensor output voltage:  

$$V_{Sensor,typ} = TC_{Sensor} (273 + T [^\circ\text{C}]) + V_{Offset,sensor} [\text{mV}] \text{ or}$$

$$V_{Sensor,typ} = TC_{Sensor} T [^\circ\text{C}] + V_{Sensor}(T_A = 0^\circ\text{C}) [\text{mV}]$$
- (3) The typical equivalent impedance of the sensor is 51 k $\Omega$ . The sample time required includes the sensor-on time  $t_{SENSOR(on)}$ .
- (4) No additional current is needed. The  $V_{MID}$  is used during sampling.
- (5) The on-time  $t_{VMID(on)}$  is included in the sampling time  $t_{VMID(sample)}$ ; no additional on time is needed.

## Flash Memory

over recommended ranges of supply voltage and up to operating free-air temperature,  $T_A = 105^\circ\text{C}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS	$V_{CC}$	MIN	TYP	MAX	UNIT
$V_{CC(PGM/ERASE)}$	Program and erase supply voltage			2.2		3.6	V
$f_{FTG}$	Flash timing generator frequency			257		476	kHz
$I_{PGM}$	Supply current from $V_{CC}$ during program		3 V		1	5	mA
$I_{ERASE}$	Supply current from $V_{CC}$ during erase		3 V		1	7	mA
$t_{CPT}$	Cumulative program time <sup>(1)</sup>		2.2 V/3.6 V			10	ms
$t_{CMErase}$	Cumulative mass erase time		2.2 V/3.6 V	20			ms
	Program/erase endurance	$-40^\circ\text{C} \leq T_J \leq 105^\circ\text{C}$		$10^4$	$10^5$		cycles
$t_{Retention}$	Data retention duration	$T_J = 25^\circ\text{C}$		15			years
$t_{Word}$	Word or byte program time	(2)			30		$t_{FTG}$
$t_{Block, 0}$	Block program time for first byte or word	(2)			25		$t_{FTG}$
$t_{Block, 1-63}$	Block program time for each additional byte or word	(2)			18		$t_{FTG}$
$t_{Block, End}$	Block program end-sequence wait time	(2)			6		$t_{FTG}$
$t_{Mass Erase}$	Mass erase time	(2)			10593		$t_{FTG}$
$t_{Seg Erase}$	Segment erase time	(2)			4819		$t_{FTG}$

- (1) The cumulative program time must not be exceeded when writing to a 64-byte flash block. This parameter applies to all programming methods: individual word/byte write and block write modes.
- (2) These values are hardwired into the Flash Controller's state machine ( $t_{FTG} = 1/f_{FTG}$ ).

## RAM

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	MAX	UNIT
$V_{(RAMh)}$	RAM retention supply voltage <sup>(1)</sup>	CPU halted	1.6		V

- (1) This parameter defines the minimum supply voltage  $V_{CC}$  when the data in RAM remains unchanged. No program execution should happen during this supply voltage condition.

## JTAG and Spy-Bi-Wire Interface

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	$V_{CC}$	MIN	TYP	MAX	UNIT
$f_{SBW}$	Spy-Bi-Wire input frequency		2.2 V/3 V	0		20	MHz
$t_{SBW,Low}$	Spy-Bi-Wire low clock pulse length		2.2 V/3 V	0.025		15	$\mu$ s
$t_{SBW,En}$	Spy-Bi-Wire enable time (TEST high to acceptance of first clock edge <sup>(1)</sup> )		2.2 V/3 V			1	$\mu$ s
$t_{SBW,Ret}$	Spy-Bi-Wire return to normal operation time	$T_A = -40^{\circ}\text{C}$ to $105^{\circ}\text{C}$	2.2 V/3 V	15		100	$\mu$ s
$f_{TCK}$	TCK input frequency <sup>(2)</sup>		2.2 V	0		5	MHz
			3 V	0		10	MHz
$R_{Internal}$	Internal pulldown resistance on TEST	$T_A = -40^{\circ}\text{C}$ to $105^{\circ}\text{C}$	2.2 V/3 V	25	60	90	k $\Omega$

- (1) Tools accessing the Spy-Bi-Wire interface need to wait for the maximum  $t_{SBW,En}$  time after pulling the TEST/SBWCLK pin high before applying the first SBWCLK clock edge.  
 (2)  $f_{TCK}$  may be restricted to meet the timing requirements of the module selected.

## JTAG Fuse<sup>(1)</sup>

$T_A = 25^{\circ}\text{C}$ , over recommended ranges of supply voltage (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	MAX	UNIT
$V_{CC(FB)}$	Supply voltage during fuse-blow condition		2.5		V
$V_{FB}$	Voltage level on TEST for fuse blow		6	7	V
$I_{FB}$	Supply current into TEST during fuse blow			100	mA
$t_{FB}$	Time to blow fuse			1	ms

- (1) Once the fuse is blown, no further access to the JTAG/Test, Spy-Bi-Wire, and emulation feature is possible, and JTAG is switched to bypass mode.

APPLICATION INFORMATION

Port P1 Pin Schematic: P1.0 to P1.2, Input/Output With Schmitt Trigger

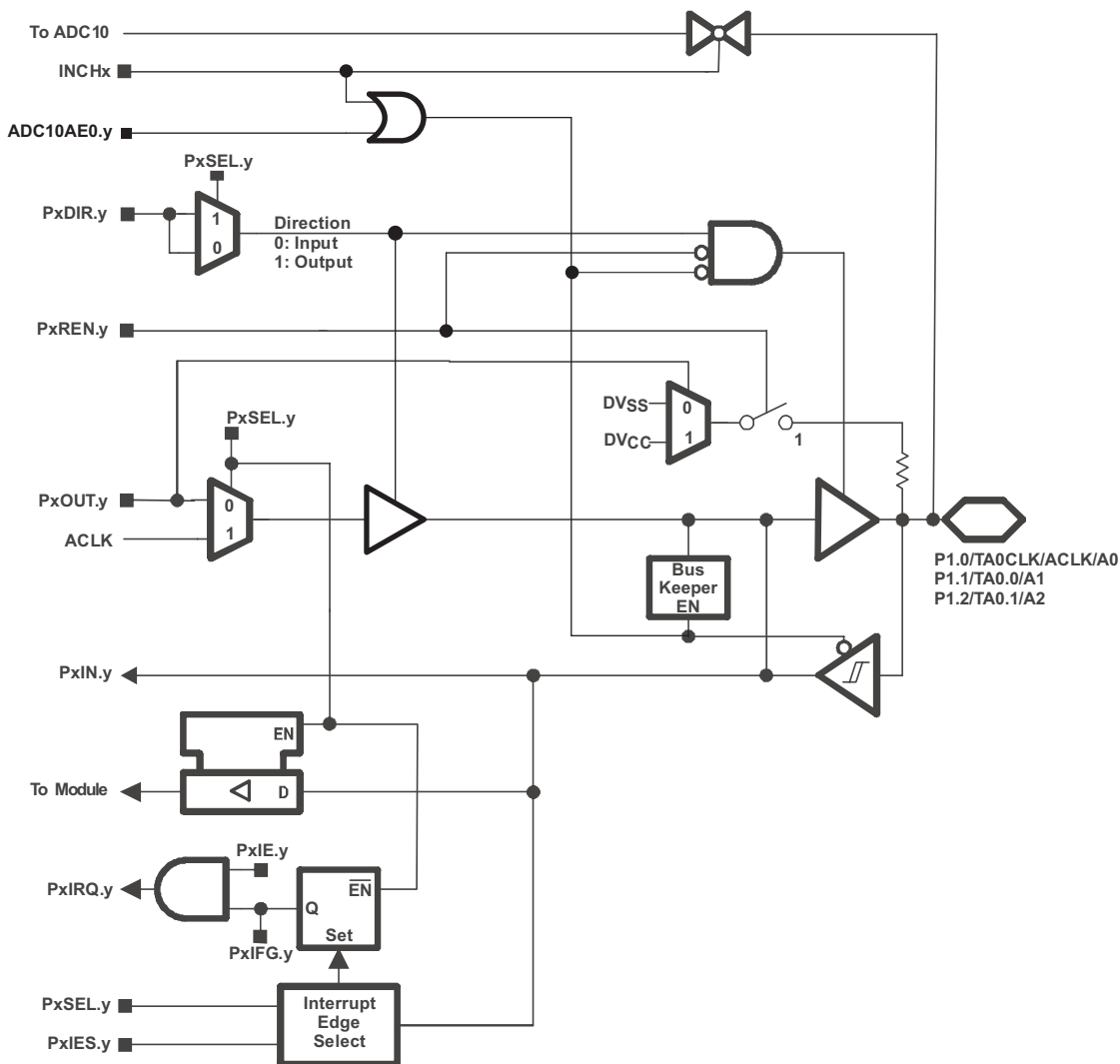


Table 14. Port P1 (P1.0 to P1.2) Pin Functions

PIN NAME (P1.x)	x	FUNCTION	CONTROL BITS / SIGNALS		
			P1DIR.x	P1SEL.x	ADC10AE.x (INCH.y = 1)
P1.0/ TA0CLK/ ACLK/ A0	0	P1.x (I/O)	I: 0; O: 1	0	0
		TA0.TACLK	0	1	0
		ACLK	1	1	0
		A0	X	X	1 (y = 0)
P1.1/ TA0.0/ A1	1	P1.x (I/O)	I: 0; O: 1	0	0
		TA0.0	1	1	0
		TA0.CCI0A	0	1	0
		A1	X	X	1 (y = 1)

**Table 14. Port P1 (P1.0 to P1.2) Pin Functions (continued)**

PIN NAME (P1.x)	x	FUNCTION	CONTROL BITS / SIGNALS		
			P1DIR.x	P1SEL.x	ADC10AE.x (INCH.y = 1)
P1.2/ TA0.1/	2	P1.x (I/O)	I: 0; O: 1	0	0
		TA0.1	1	1	0
		TA0.CCI1A	0	1	0
A2/		A2	X	X	1 (y = 2)



Port P1 Pin Schematic: P1.3, Input/Output With Schmitt Trigger

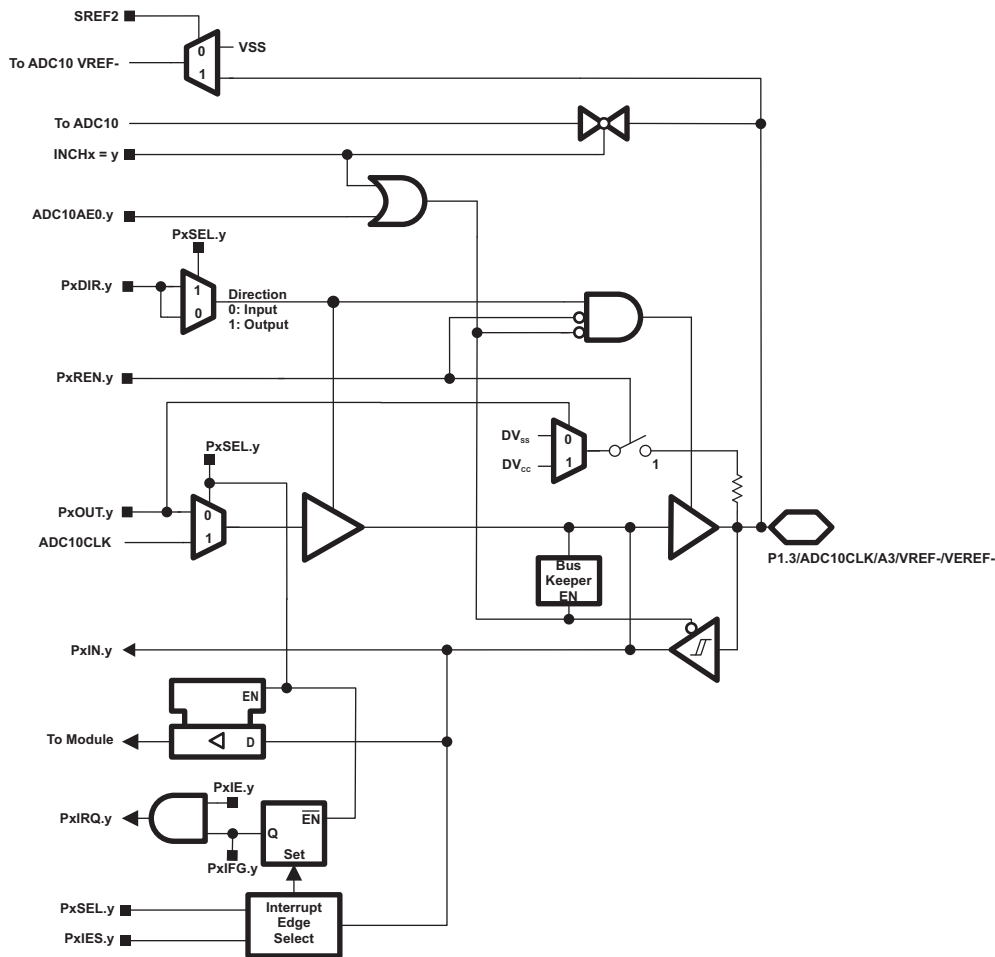


Table 15. Port P1 (P1.3) Pin Functions

PIN NAME (P1.x)	x	FUNCTION	CONTROL BITS / SIGNALS		
			P1DIR.x	P1SEL.x	ADC10AE.x (INCH.x = 1)
P1.3/ ADC10CLK/ A3/ VREF-/ VEREF-	3	P1.x (I/O)	I: 0; O: 1	0	0
		ADC10CLK	1	1	0
		A3	X	X	1 (y = 3)
		VREF-	X	X	1
		VEREF-	X	X	1

Port P1 Pin Schematic: P1.4, Input/Output With Schmitt Trigger

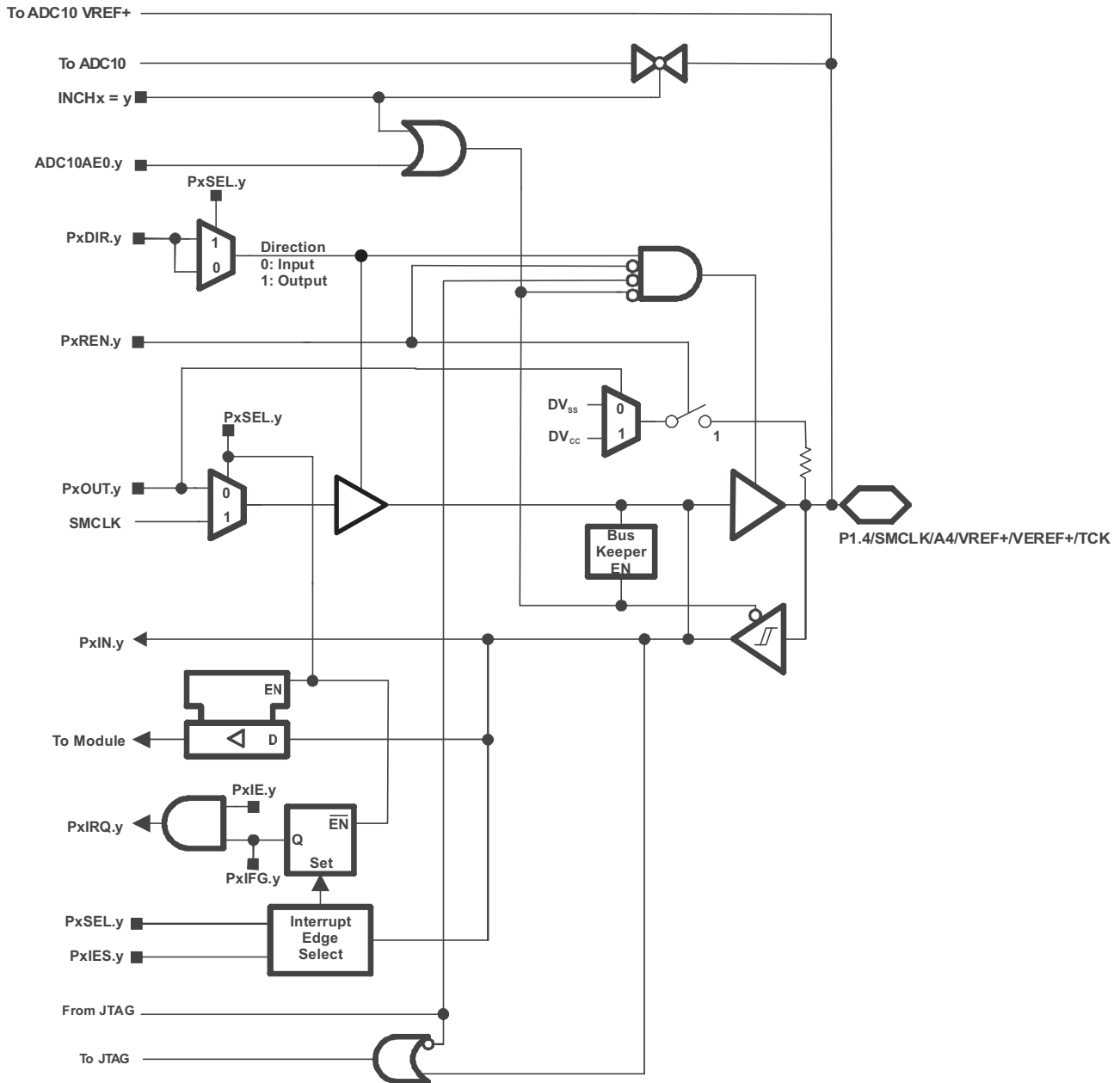


Table 16. Port P1 (P1.4) Pin Functions

PIN NAME (P1.x)	x	FUNCTION	CONTROL BITS / SIGNALS			
			P1DIR.x	P1SEL.x	ADC10AE.x (INCH.x = 1)	JTAG Mode
P1.4/	4	P1.x (I/O)	I: 0; O: 1	0	0	0
SMCLK/		SMCLK	1	1	0	0
A4/		A4	X	X	1 (y = 4)	0
VREF+/		VREF+	X	X	1	0
VEREF+/		VEREF+	X	X	1	0
TCK		TCK	X	X	0	1

Port P1 Pin Schematic: P1.5, Input/Output With Schmitt Trigger

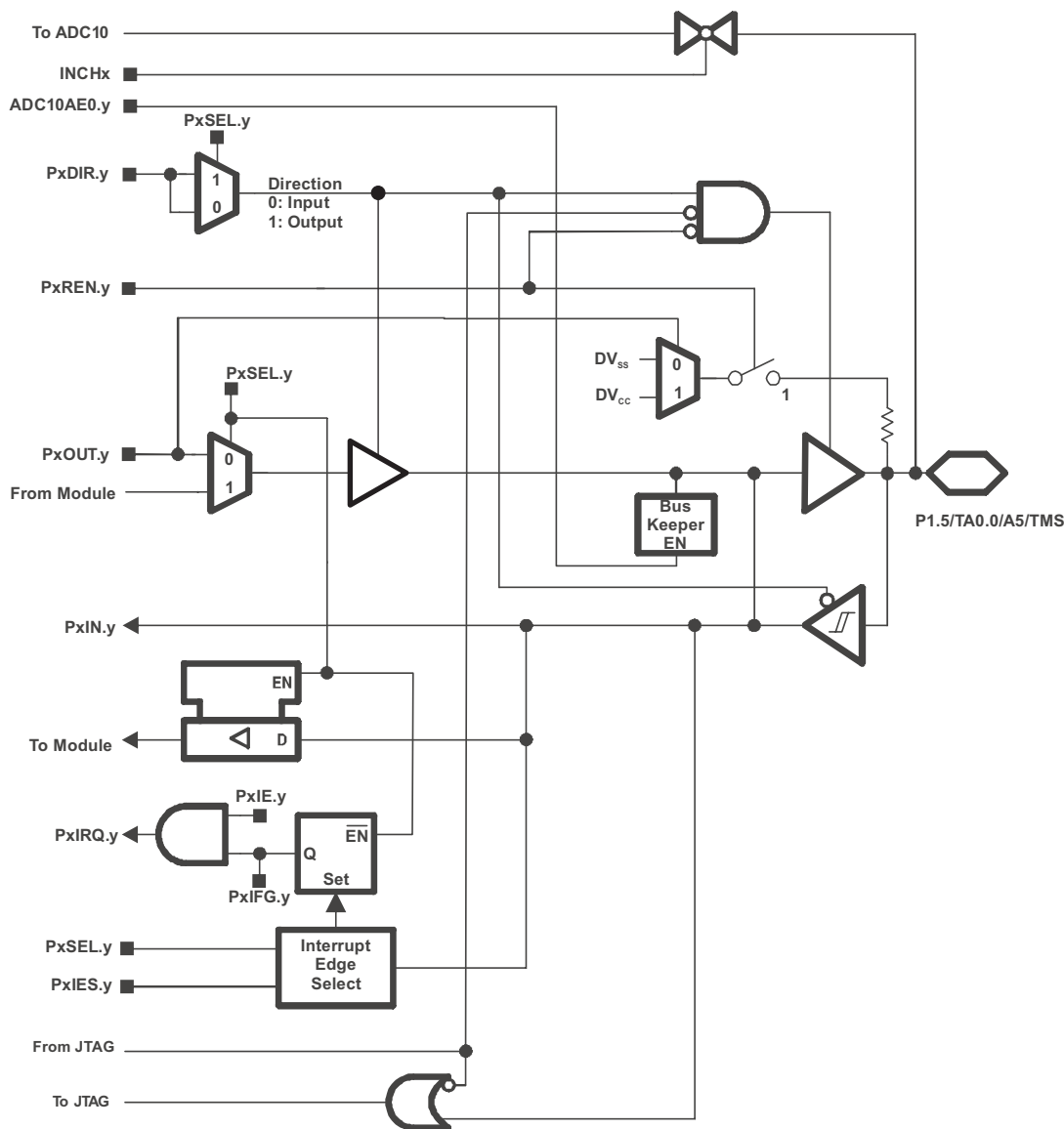
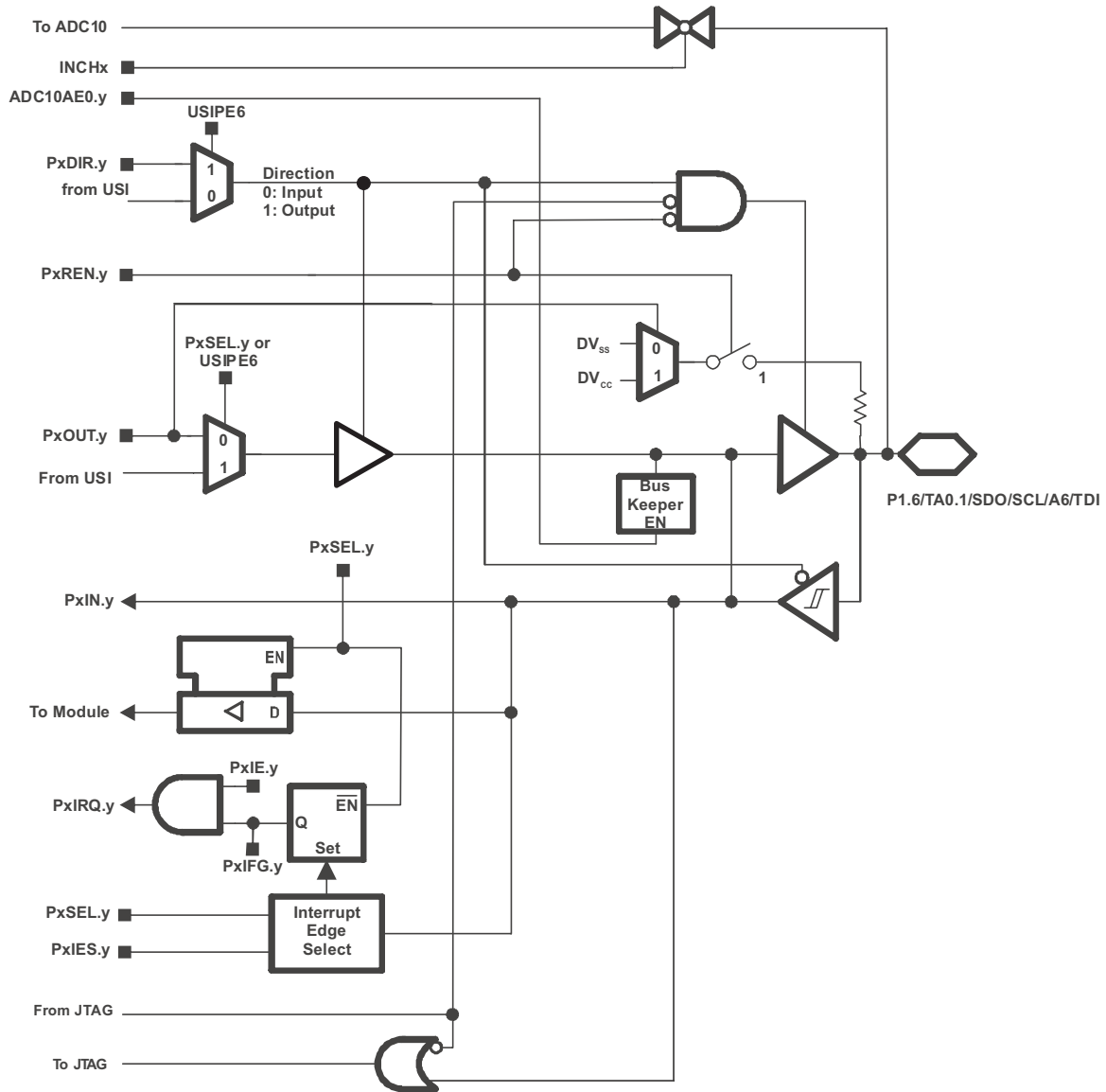


Table 17. Port P1 (P1.5) Pin Functions

PIN NAME (P1.x)	x	FUNCTION	CONTROL BITS / SIGNALS				
			P1DIR.x	P1SEL.x	USIP.x	ADC10AE.x (INCH.x = 1)	JTAG Mode
P1.5/ TA0.0/ A5/ SCLK/ TMS	5	P1.x (I/O)	I: 0; O: 1	0	0	0	0
TA0.0		1	1	0	0	0	
A5		X	X	X	1 (y = 5)	0	
SCLK		X	X	1	0	0	
TMS		X	X	0	0	1	

**Port P1 Pin Schematic: P1.6, Input/Output With Schmitt Trigger**

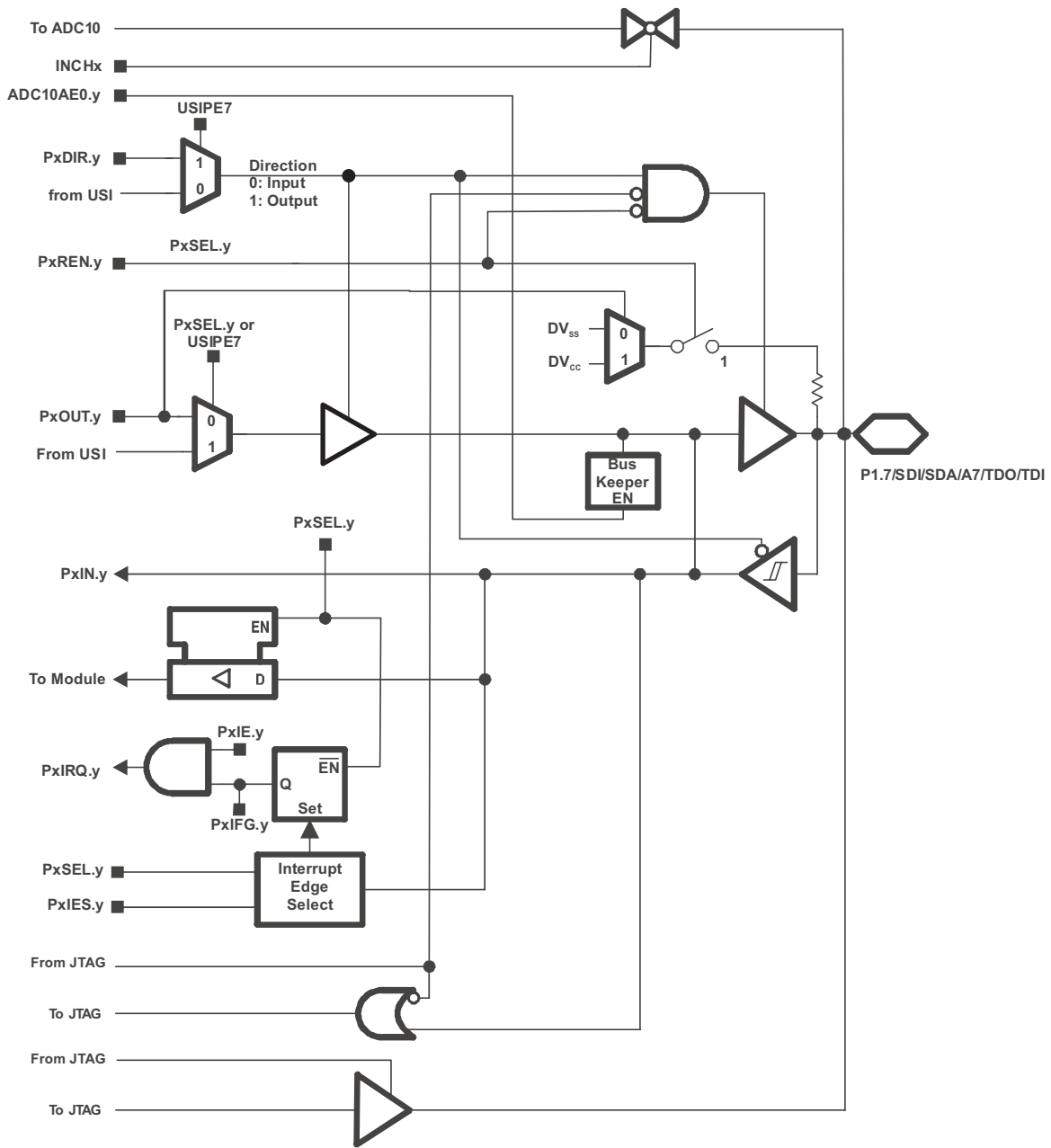


USI in I2C mode: Output driver drives low level only. Driver is disabled in JTAG mode.

**Table 18. Port P1 (P1.6) Pin Functions**

PIN NAME (P1.x)	x	FUNCTION	CONTROL BITS / SIGNALS				
			P1DIR.x	P1SEL.x	USIP.x	ADC10AE.x (INCH.x = 1)	JTAG Mode
P1.6/ TA0.1/	6	P1.x (I/O)	I: 0; O: 1	0	0	0	0
		TA0.1	1	1	0	0	0
		TA0.CCR1B	0	1	0	0	0
A6/		A6	X	X	0	1 (y = 6)	0
SDO/		SDO	X	X	1	0	0
TDI/TCLK		TDI/TCLK	X	X	0	0	1

Port P1 Pin Schematic: P1.7, Input/Output With Schmitt Trigger



US1 in I2C mode: Output driver drives low level only. Driver is disabled in JTAG mode.

Table 19. Port P1 (P1.7) Pin Functions

PIN NAME (P1.x)	x	FUNCTION	CONTROL BITS / SIGNALS				
			P1DIR.x	P1SEL.x	USIP.x	ADC10AE.x (INCH.x = 1)	JTAG Mode
P1.7/	7	P1.x (I/O)	I: 0; O: 1	0	0	0	0
A7/		A7	X	X	0	1 (y = 7)	0
SDI/SDO		SDI/SDO	X	X	1	0	0
TDO/TDI		TDO/TDI	X	X	0	0	1

Port P2 Pin Schematic: P2.6, Input/Output With Schmitt Trigger

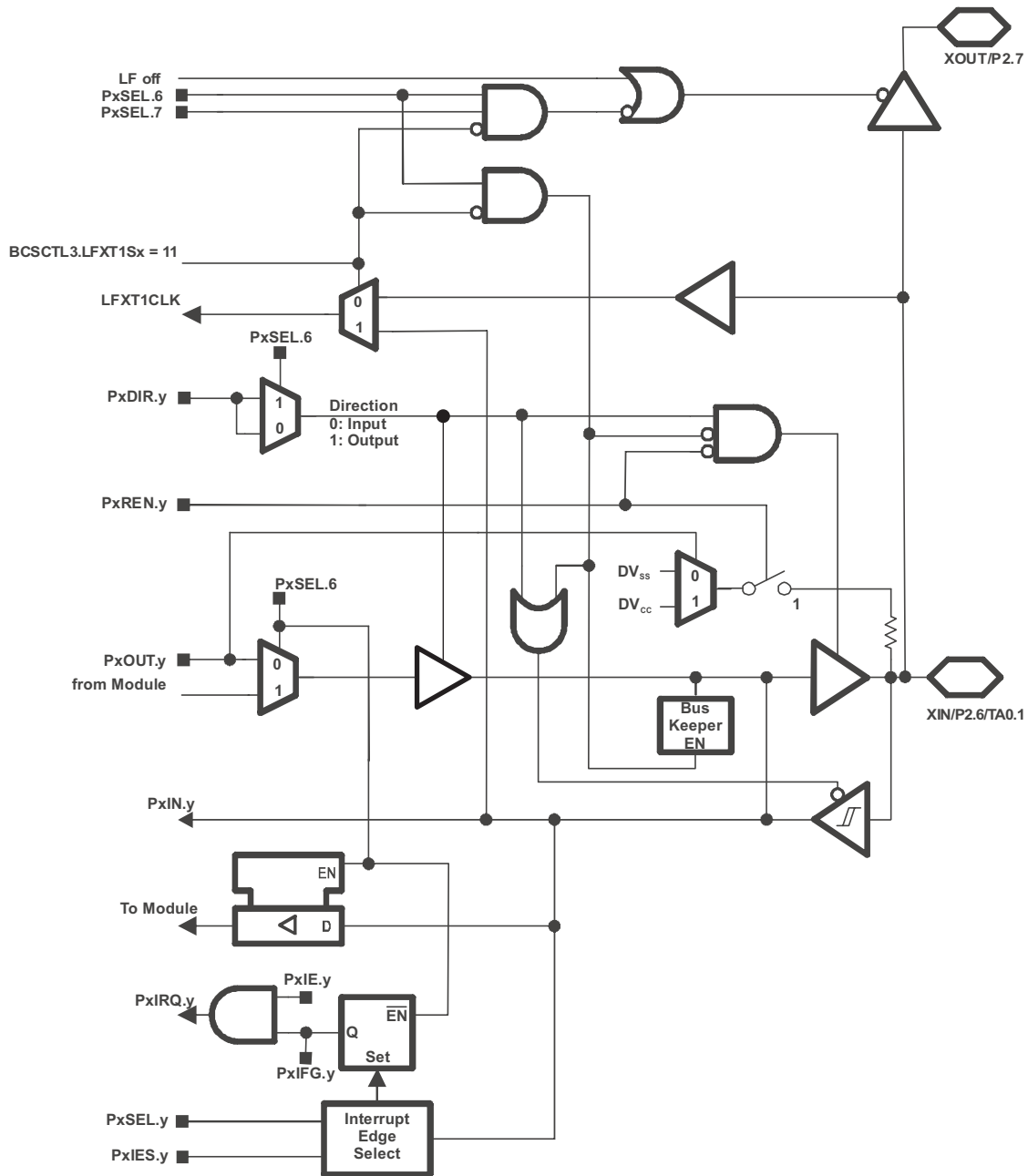


Table 20. Port P2 (P2.6) Pin Functions

PIN NAME (P2.x)	x	FUNCTION	CONTROL BITS / SIGNALS		
			P2DIR.x	P2SEL.6	P2SEL.7
XIN	6	XIN	0	1	1
P2.6		P2.x (I/O)	I: 0; O: 1	0	X
TA0.1		TA0.1 <sup>(1)</sup>	1	1	X

(1) BCSCTL3.LFXT1Sx = 11 is required.

Port P2 Pin Schematic: P2.7, Input/Output With Schmitt Trigger

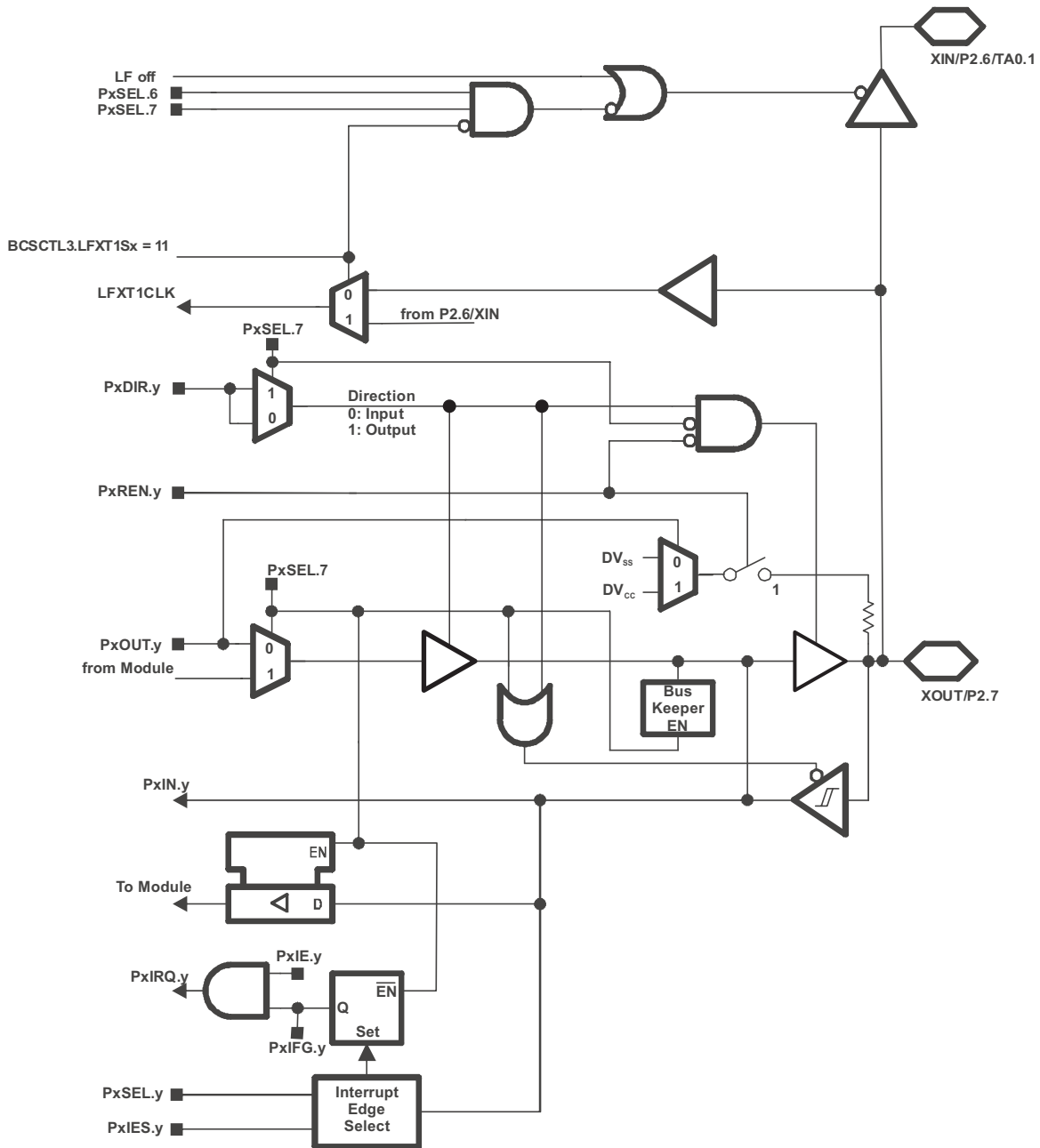


Table 21. Port P2 (P2.7) Pin Functions

PIN NAME (P2.x)	x	FUNCTION	CONTROL BITS / SIGNALS		
			P2DIR.x	P2SEL.6	P2SEL.7
XOUT	7	XOUT	1	1	1
P2.7		P2.x (I/O)	I: 0; O: 1	X	0

**PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
MSP430G2231QPW1EP	ACTIVE	TSSOP	PW	14	90	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 125	G2231EP	<a href="#">Samples</a>
MSP430G2231QPW1REP	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 125	G2231EP	<a href="#">Samples</a>
V62/12621-01XE	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 125	G2231EP	<a href="#">Samples</a>
V62/12621-01XE-T	ACTIVE	TSSOP	PW	14	90	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 125	G2231EP	<a href="#">Samples</a>

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) **MSL, Peak Temp.** - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "-" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) **Lead finish/Ball material** - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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**OTHER QUALIFIED VERSIONS OF MSP430G2231-EP :**

- Catalog: [MSP430G2231](#)
- Automotive: [MSP430G2231-Q1](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

PW0014A



# PACKAGE OUTLINE

## TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



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### NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-153.

# EXAMPLE BOARD LAYOUT

PW0014A

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



LAND PATTERN EXAMPLE  
EXPOSED METAL SHOWN  
SCALE: 10X



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NOTES: (continued)

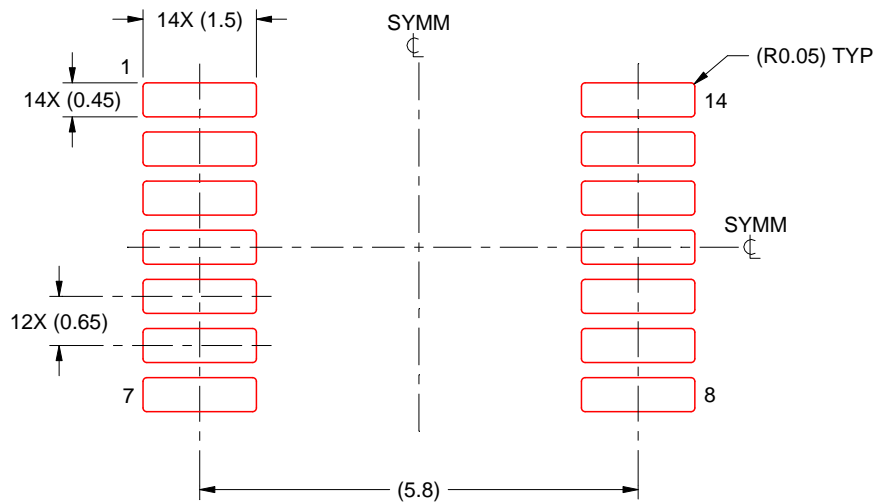
- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

# EXAMPLE STENCIL DESIGN

PW0014A

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



SOLDER PASTE EXAMPLE  
BASED ON 0.125 mm THICK STENCIL  
SCALE: 10X

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NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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